- Low Supply-Voltage Range, 1.8 V to 3.6 V
- Ultra-Low Power Consumption:
 - Active Mode: 200 μA at 1 MHz, 2.2 V
 - Standby Mode: 0.7 μA
 - Off Mode (RAM Retention): 0.1 μ A
- Ultra-Fast Wake-Up From Standby Mode in Less Than 1 μs
- 16-Bit RISC Architecture,
 62.5-ns Instruction Cycle Time
- Basic Clock Module Configurations:
 - Internal Frequencies up to 16 MHz With Four Calibrated Frequencies to ±1%
 - Internal Very Low-Power Low-Frequency Oscillator
 - 32-kHz Crystal
 - High-Frequency Crystal up to 16 MHz
 - Resonator
 - External Digital Clock Source
 - External Resistor
- 16-Bit Timer0_A3 With Three Capture/Compare Registers
- 16-Bit Timer1_A2 With Two Capture/Compare Registers
- On-Chip Comparator for Analog Signal Compare Function or Slope Analog-to-Digital (A/D) Conversion
- 10-Bit, 200-ksps A/D Converter With Internal Reference, Sample-and-Hold, Autoscan, and Data Transfer Controller

- Universal Serial Communication Interface
 - Enhanced UART Supporting Auto Baudrate Detection (LIN)
 - IrDA Encoder and Decoder
 - Synchronous SPI
 - I²C™
- Brownout Detector
- Serial Onboard Programming, No External Programming Voltage Needed, Programmable Code Protection by Security Fuse
- Bootstrap Loader in Flash Devices
- On-Chip Emulation Module
- Family Members Include: MSP430F2132
 - 8KB + 256B Flash Memory
 - 512B RAM

MSP430F2122

- 4KB + 256B Flash Memory
- 512B RAM

MSP430F2112

- 2kB + 256B Flash Memory
- 256B RAM
- Available in 28-Pin TSSOP and 32-Pin QFN (See Available Options)
- For Complete Module Descriptions, See the MSP430x2xx Family User's Guide, Literature Number SLAU144

description

The Texas Instruments MSP430 family of ultra-low-power microcontrollers consists of several devices featuring different sets of peripherals targeted for various applications. The architecture, combined with five low-power modes, is optimized to achieve extended battery life in portable measurement applications. The device features a powerful 16-bit RISC CPU, 16-bit registers, and constant generators that contribute to maximum code efficiency. The digitally controlled oscillator (DCO) allows wake-up from low-power modes to active mode in less than 1 μ s.

The MSP430F21x2 series is an ultra-low-power microcontroller with two built-in 16-bit timers, a fast 10-bit A/D converter with integrated reference and a data transfer controller (DTC), a comparator, built-in communication capability using the universal serial communication interface, and up to 24 I/O pins.



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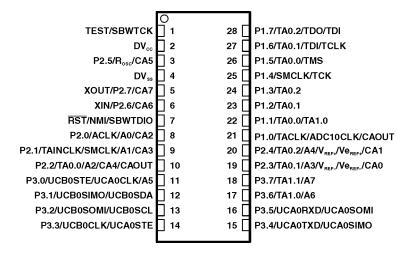
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AVAILABLE OPTIONS

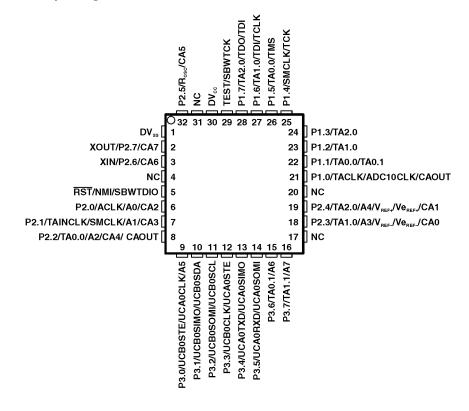
_	PACKAGED DEVICES						
T _A	PLASTIC 28-PIN TSSOP (PW)	PLASTIC 32-PIN QFN (RHB)					
	MSP430F2112IPW	MSP430F2112IRHB					
-40°C to 85°C	MSP430F2122IPW	MSP430F2122IRHB					
	MSP430F2132IPW	MSP430F2132IRHB					
	MSP430F2112TPW	MSP430F2112TRHB					
-40°C to 105°C	MSP430F2122TPW	MSP430F2122TRHB					
	MSP430F2132TPW	MSP430F2132TRHB					



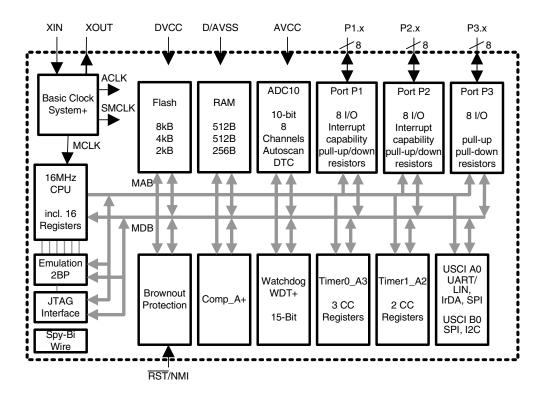
pin designation, PW package



pin designation, RHB package



functional block diagram



Terminal Functions

TERMINAL						
NAME	28-Pin PW	32-Pin RHB	I/O	DESCRIPTION		
P1.0/TACLK/ ADC10CLK/CAOUT	21	21	I/O	General-purpose digital I/O pin Timer0_A3, clock signal TACLK input Timer1_A2, clock signal TACLK input ADC10, conversion clock Comparator_A+ output		
P1.1/TA0.0/TA1.0	22	22	I/O	General-purpose digital I/O pin Timer0_A3, capture: CCl0A input, compare: Out0 Output Timer1_A2, capture: CCl0A input		
P1.2/TA0.1	23	23	I/O	General-purpose digital I/O pin Timer0_A3, capture: CCI1A input, compare: Out1 Output		
P1.3/TA0.2	24	24	I/O	General-purpose digital I/O pin Timer0_A3, capture: CCl2A input, compare: Out2 Output		
P1.4/SMCLK/TCK	25	25	I/O	General-purpose digital I/O pin SMCLK signal output Test Clock input for device programming and test		
P1.5/TA0.0/TMS	26	26	I/O	General-purpose digital I/O pin Timer0_A3, compare: Out0 Output JTAG test mode select, input terminal for device programming and test		
P1.6/TA0.1/TDI/TCLK	27	27	I/O	General-purpose digital I/O pin Timer0_A3, compare: Out1 Output JTAG test data input or test clock input in programming an test		
P1.7/TA0.2/TDO/TDI	28	28	I/O	General-purpose digital I/O pin Timer0_A3, compare: Out2 Output JTAG test data output terminal or test data input in programming an test		
P2.0/ACLK/A0/CA2	8	6	I/O	General-purpose digital I/O pin ACLK signal output ADC10 analog input A0 Comparator_A+ input		
P2.1/TAINCLK/ SMCLK/A1/CA3	9	7	I/O	General-purpose digital I/O pin SMCLK signal output Timer0_A3, clock signal TACLK input Timer1_A2, clock signal TACLK input ADC10 analog input A1 Comparator_A+ input		
P2.2/TA0.0/A2/CA4/ CAOUT	10	8	I/O	General-purpose digital I/O pin Timer0_A3, capture: CCI0B input, compare: Out0 Output ADC10 analog input A2 Comparator_A+ input Comparator_A+ output		
P2.3/TA0.1/A3/ V _{REF-} /Ve _{REF-} /CA0	19	18	I/O	General-purpose digital I/O pin Timer0_A3, compare: Out1 Output ADC10 analog input A3 / negative reference Comparator_A+ input		
P2.4/TA0.2/A4/ V _{REF+} /Ve _{REF+} /CA1	20	19	I/O	General-purpose digital I/O pin Timer0_A3, compare: Out2 Output ADC10 analog input A4 / positive reference Comparator_A+ input		



Terminal Functions (continued)

TERMINAL					
NAME	28-Pin PW	32-Pin RHB	I/O	DESCRIPTION	
XIN/P2.6/CA6	6	3	I/O	Input terminal of crystal oscillator General-purpose digital I/O pin Comparator_A+ input	
XOUT/P2.7/CA7	5	2	I/O	Output terminal of crystal oscillator General-purpose digital I/O pin Comparator_A+ input	
P3.0/UCB0STE/ UCA0CLK/A5	11	9	I/O	General-purpose digital I/O pin USCI_B0 slave transmit enable/USCI_A0 clock input/output ADC10 analog input A5	
P3.1/UCB0SIMO/ UCB0SDA	12	10	I/O	General-purpose digital I/O pin USCI_B0 slave in/master out in SPI mode, SDA I ² C data in I ² C mode	
P3.2/UCB0SOMI/ UCB0SCL	13	11	I/O	General-purpose digital I/O pin USCI_B0 slave out/master in in SPI mode, SCL I ² C clock in I ² C mode	
P3.3/UCB0CLK/ UCA0STE	14	12	I/O	General-purpose digital I/O USCI_B0 clock input/output, USCI_A0 slave transmit enable	
P3.4/UCA0TXD/ UCA0SIMO	15	13	I/O	General-purpose digital I/O pin USCI_A0 transmit data output in UART mode, slave data in/master out in SPI mode	
P3.5/UCA0RXD/ UCA0SOMI	16	14	I/O	General-purpose digital I/O pin USCI_A0 receive data input in UART mode, slave data out/master in in SPI mode	
P3.6/TA1.0/A6	17	15	I/O	General-purpose digital I/O pin Timer1_A2, capture: CCI0B input, compare: Out0 Output ADC10 analog input A6	
P3.7/TA1.1/A7	18	16	I/O	General-purpose digital I/O pin Timer1_A2, capture: CCI1A input, compare: Out1 Output ADC10 analog input A7	
RST/NMI/SBWTDIO	7	5	I	Reset or nonmaskable interrupt input Spy-Bi-Wire test data input/output during programming and test	
TEST/SBWTCK	1	29	I	Selects test mode for JTAG pins on Port1. The device protection fuse is connected to TEST.	
P2.5/R _{OSC} /CA5	3	32	I/O	General-purpose digital I/O pin Input for external resistor defining the DCO nominal frequency Comparator_A+ input	
DV _{CC}	2	30		Digital supply voltage	
DV _{SS}	4	1		Digital supply voltage	
NC	NA	4, 17, 20, 31		Not connected internally. Connection to V _{SS} is recommended.	
QFN Pad	NA	NA	NA	QFN package pad (RHB package only). Connection to DV _{SS} is recommended.	



short-form description

CPU

The MSP430 CPU has a 16-bit RISC architecture that is highly transparent to the application. All operations, other than program-flow instructions, are performed as register operations in conjunction with seven addressing modes for source operand and four addressing modes for destination operand.

The CPU is integrated with 16 registers that provide reduced instruction execution time. The register-to-register operation execution time is one cycle of the CPU clock.

Four of the registers, R0 to R3, are dedicated as program counter, stack pointer, status register, and constant generator, respectively. The remaining registers are general-purpose registers.

Peripherals are connected to the CPU using data, address, and control buses, and can be handled with all instructions.

instruction set

The instruction set consists of 51 instructions with three formats and seven address modes. Each instruction can operate on word and byte data. Table 1 shows examples of the three types of instruction formats; the address modes are listed in Table 2.



Table 1. Instruction Word Formats

Dual operands, source-destination	e.g., ADD R4,R5	R4 + R5> R5
Single operands, destination only	e.g., CALL R8	PC>(TOS), R8> PC
Relative jump, un/conditional	e.g., JNE	Jump-on-equal bit = 0

Table 2. Address Mode Descriptions

ADDRESS MODE	s	D	SYNTAX	EXAMPLE	OPERATION
Register	•	•	MOV Rs,Rd	MOV R10,R11	R10> R11
Indexed	•	•	MOV X(Rn),Y(Rm)	MOV 2(R5),6(R6)	M(2+R5)> M(6+R6)
Symbolic (PC relative)	•	•	MOV EDE,TONI		M(EDE)> M(TONI)
Absolute	•	•	MOV &MEM,&TCDAT		M(MEM)> M(TCDAT)
Indirect	•		MOV @Rn,Y(Rm)	MOV @R10,Tab(R6)	M(R10)> M(Tab+R6)
Indirect autoincrement	•		MOV @Rn+,Rm	MOV @R10+,R11	M(R10)> R11 R10 + 2> R10
Immediate	•		MOV #X,TONI	MOV #45,TONI	#45> M(TONI)

NOTE: S = source D = destination



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operating modes

The MSP430 has one active mode and five software-selectable low-power modes of operation. An interrupt event can wake up the device from any of the five low-power modes, service the request, and restore back to the low-power mode on return from the interrupt program.

The following six operating modes can be configured by software:

- Active mode (AM)
 - All clocks are active.
- Low-power mode 0 (LPM0)
 - CPU is disabled.
 - ACLK and SMCLK remain active, MCLK is disabled.
- Low-power mode 1 (LPM1)
 - CPU is disabled.
 - ACLK and SMCLK remain active, MCLK is disabled.
 - DCO's dc generator is disabled if DCO not used in active mode.
- Low-power mode 2 (LPM2)
 - CPU is disabled.
 - MCLK and SMCLK are disabled.
 - DCO's dc generator remains enabled.
 - ACLK remains active.
- Low-power mode 3 (LPM3)
 - CPU is disabled.
 - MCLK and SMCLK are disabled.
 - DCO's dc-generator is disabled.
 - ACLK remains active.
- Low-power mode 4 (LPM4)
 - CPU is disabled.
 - ACLK is disabled.
 - MCLK and SMCLK are disabled.
 - DCO's dc generator is disabled.
 - Crystal oscillator is stopped.



interrupt vector addresses

The interrupt vectors and the power-up starting address are located in the address range 0xFFFF to 0xFFC0. The vector contains the 16-bit address of the appropriate interrupt-handler instruction sequence. If the reset vector (0xFFFE) contains 0xFFFF (e.g., flash is not programmed) the CPU enters LPM4 after power-up.

INTERRUPT SOURCE	INTERRUPT FLAG	SYSTEM INTERRUPT	WORD ADDRESS	PRIORITY
Power-up External reset Watchdog Flash key violation PC out of range (see Note 1)	PORIFG RSTIFG WDTIFG KEYV (see Note 2)	Reset	0xFFFE	31, highest
NMI Oscillator fault Flash memory access violation	NMIIFG OFIFG ACCVIFG (see Notes 2 and 6)	(Non)maskable (Non)maskable (Non)maskable	0xFFFC	30
Timer1_A2	TA1CCR0 CCIFG (see Note 3)	Maskable	0xFFFA	29
Timer1_A2	TA1CCR1 CCIFG, TA1CTL TAIFG (see Notes 2 and 3)	Maskable	0xFFF8	28
Comparator_A+	CAIFG	Maskable	0xFFF6	27
Watchdog timer	WDTIFG	Maskable	0xFFF4	26
Timer0_A3	TA0CCR0 CCIFG (see Note 3)	Maskable	0xFFF2	25
Timer0_A3	TA0CCR1 CCIFG, TA0CCR2 CCIFG, TA0CTL TAIFG (see Notes 2 and 3)	Maskable	0xFFF0	24
USCI_A0/USCI_B0 receive USCI_B0 I2C status	UCA0RXIFG, UCB0RXIFG (see Note 2 and 4)	Maskable	0xFFEE	23
USCI_A0/USCI_B0 transmit USCI_B0 I2C receive/transmit	UCA0TXIFG, UCB0TXIFG (see Note 2 and 5)	Maskable	0xFFEC	22
ADC10	ADC10IFG (see Note 3)	Maskable	0xFFEA	21
			0xFFE8	20
I/O port P2 (eight flags)	P2IFG.0 to P2IFG.7 (see Notes 2 and 3)	Maskable	0xFFE6	19
I/O port P1 (eight flags)	P1IFG.0 to P1IFG.7 (see Notes 2 and 3)	Maskable	0xFFE4	18
			0xFFE2	17
			0xFFE0	16
(See Note 7)			0xFFDE	15
(See Note 8)			0xFFDC to 0xFFC0	14 to 0, lowest

NOTES: 1. A reset is executed if the CPU tries to fetch instructions from within the module register memory address range (0x0000 to 0x01FF).

- 2. Multiple source flags.
- 3. Interrupt flags are located in the module.
- 4. In SPI mode: UCB0RXIFG. In I2C mode: UCALIFG, UCNACKIFG, ICSTTIFG, UCSTPIFG.
- 5. In UART/SPI mode: UCB0TXIFG. In I2C mode: UCB0RXIFG, UCB0TXIFG.
- 6. (Non)maskable: the individual interrupt-enable bit can disable an interrupt event, but the general interrupt enable cannot.
- 7. This location is used as bootstrap loader security key (BSLSKEY).
 - A 0xAA55 at this location disables the BSL completely.
 - A zero (0h) disables the erasure of the flash if an invalid password is supplied.
- 8. The interrupt vectors at addresses 0xFFDC to 0xFFC0 are not used in this device and can be used for regular program code if necessary.



special function registers

Most interrupt and module-enable bits are collected in the lowest address space. Special-function register bits not allocated to a functional purpose are not physically present in the device. This arrangement provides simple software access.

interrupt enable 1 and 2

Address	7	6	5	4	3	2	1	0		
00h			ACCVIE	NMIIE			OFIE	WDTIE		
			rw-0	rw-0			rw-0	rw-0		
WDTIE		Watchdog timer interrupt enable. Inactive if watchdog mode is selected. Active if watchdog timer is configured in interval timer mode.								
OFIE	Oscilla	tor fault ena	ble							
NMIIE	(Non)n	naskable int	errupt enab	le						
ACCVIE	Flash access violation interrupt enable									
Address	7	6	5	4	3	2	1	0	_	
01h					UCB0TXIE	UCB0RXIE	UCA0TXIE	UCA0RXIE		

rw-0

rw-0

rw-0

rw-0

UCAORXIE USCI_A0 receive interrupt enable
UCAOTXIE USCI_A0 transmit interrupt enable
UCBORXIE USCI_B0 receive interrupt enable
UCBOTXIE USCI_B0 transmit interrupt enable

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interrupt flag register 1 and 2

Address	7	6	5	4	3	2	1	0
02h				NMIIFG	RSTIFG	PORIFG	OFIFG	WDTIFG
				rw-0	rw-(0)	rw-(1)	rw-1	rw-(0)

WDTIFG Set on watchdog timer overflow or security key violation.

Reset on V_{CC} power-up or a reset condition at \overline{RST}/NMI pin in reset mode.

OFIFG Flag set on oscillator fault

RSTIFG External reset interrupt flag. Set on a reset condition at RST/NMI pin in reset mode. Reset on

V_{CC} power up

PORIFG Power-on interrupt flag. Set on V_{CC} power-up.

NMIIFG Set via RST/NMI pin

Address 3 0 4 UCB0TX **UCBORX UCA0TX UCA0RX** 03h **IFG IFG IFG IFG** rw-0 rw-1 rw-0 rw-1

UCA0RXIFG USCI_A0 receive interrupt flag
UCA0TXIFG USCI_A0 transmit interrupt flag
UCB0RXIFG USCI_B0 receive interrupt flag
UCB0TXIFG USCI_B0 transmit interrupt flag

Legend rw: Bit can be read and written.

rw-0,1: Bit can be read and written. It is reset or set by PUC.rw-(0,1): Bit can be read and written. It is reset or set by POR.

SFR bit is not present in device

memory organization

		MSP430F2112	MSP430F2122	MSP430F2132
Memory	Size	2 KB	4 KB	8 KB
Main: interrupt vector	Flash	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0	0xFFFF to 0xFFC0
Main: code memory	Flash	0xFFFF to 0xF800	0xFFFF to 0xF000	0xFFFF to 0xE000
Information memory	Size	256 Byte	256 Byte	256 Byte
	Flash	0x10FFh to 0x1000	0x10FFh to 0x1000	0x10FFh to 0x1000
Boot memory	Size	1 KB	1 KB	1 KB
	ROM	0x0FFF to 0x0C00	0x0FFF to 0x0C00	0x0FFF to 0x0C00
RAM	Size	256 B 0x02FF to 0x0200	512 Byte 0x03FF to 0x0200	512 Byte 0x03FF to 0x0200
Peripherals	16-bit	0x01FF to 0x0100	0x01FF to 0x0100	0x01FF to 0x0100
	8-bit	0x00FF to 0x0010	0x00FF to 0x0010	0x00FF to 0x0010
	8-bit SFR	0x000F to 0x0000	0x000F to 0x0000	0x000F to 0x0000

bootstrap loader (BSL)

The MSP430 BSL enables users to program the flash memory or RAM using a UART serial interface. Access to the MSP430 memory via the BSL is protected by user-defined password. For complete description of the features of the BSL and its implementation, see the application report *Features of the MSP430 Bootstrap Loader*, literature number SLAA089.

BSL FUNCTION	28-PIN PW PACKAGE PINS	32-PIN RHB PACKAGE PINS
Data transmit	22 - P1.1	22 - P1.1
Data receive	10 - P2.2	8 - P2.2

flash memory

The flash memory can be programmed via the JTAG port, the bootstrap loader, or in-system by the CPU. The CPU can perform single-byte and single-word writes to the flash memory. Features of the flash memory include:

- Flash memory has n segments of main memory and four segments of information memory (A to D) of 64bytes each. Each segment in main memory is 512 bytes in size.
- Segments 0 to n may be erased in one step, or each segment may be individually erased.
- Segments A to D can be erased individually, or as a group with segments 0 to n.
 Segments A to D are also called information memory.
- Segment A contains calibration data. After reset segment A is protected against programming or erasing.
 It can be unlocked but care should be taken not to erase this segment if the calibration data is required.



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peripherals

Peripherals are connected to the CPU through data, address, and control buses and can be handled using all instructions. For complete module descriptions, see the MSP430x2xx Family User's Guide.

oscillator and system clock

The clock system is supported by the basic clock module that includes support for a 32768-Hz watch crystal oscillator, an internal very low power, low-frequency oscillator, an internal digitally controlled oscillator (DCO), and a high-frequency crystal oscillator. The basic clock module is designed to meet the requirements of both low system cost and low power consumption. The internal DCO provides a fast turn-on clock source and stabilizes in less than 1 µs. The basic clock module provides the following clock signals:

- Auxiliary clock (ACLK), sourced from a 32768-Hz watch crystal, a high-frequency crystal or the internal very low power LF oscillator.
- Main clock (MCLK), the system clock used by the CPU.
- Sub-Main clock (SMCLK), the subsystem clock used by the peripheral modules.

The DCO settings to calibrate the DCO output frequency are stored in the information memory segment A.



calibration data stored in information memory segment A

Calibration data is stored for both the DCO and for ADC10 organized in a tag-length-value structure.

TAGS USED BY THE ADC CALIBRATION TAGS						
NAME ADDRESS VALUE DESCRIPTION						
TAG_DCO_30	0x10F6	0x01	DCO frequency calibration at $V_{CC} = 3 \text{ V}$ and $T_A = 30^{\circ}\text{C}$ at calibration			
TAG_ADC10_1	0x10DA	0x10	ADC10_1 calibration tag			
TAG_EMPTY	-	0xFE	Identifier for empty memory areas			

LABELS USED BY THE ADC CALIBRATION TAGS						
LABEL	CONDITION AT CALIBRATION / DESCRIPTION	SIZE	ADDRESS OFFSET			
CAL_ADC_25T85	INCHx = 0x1010, REF2_5 = 1, T _A = 85°C	word	0x000E			
CAL_ADC_25T30	INCHx = 0x1010, REF2_5 = 1, T _A = 30°C	word	0x000C			
CAL_ADC_25VREF_FACTOR	REF2_5 = 1, T _A = 30°C, I _{VREF+} = 1 mA	word	0x000A			
CAL_ADC_15T85	INCHx = 0x1010, REF2_5 = 0, T _A = 85°C	word	0x0008			
CAL_ADC_15T30	INCHx = 0x1010, REF2_5 = 0, T _A = 30°C	word	0x0006			
CAL_ADC_15VREF_FACTOR	REF2_5 = 0, T _A = 30°C, I _{VREF+} = 0.5 mA	word	0x0004			
CAL_ADC_OFFSET	External V _{REF} = 1.5 V, f _{ADC10CLK} = 5 MHz	word	0x0002			
CAL_ADC_GAIN_FACTOR	External V _{REF} = 1.5 V, f _{ADC10CLK} = 5 MHz	word	0x0000			
CAL_BC1_1MHz	-	byte	0x0007			
CAL_DCO_1MHz	-	byte	0x0006			
CAL_BC1_8MHz	-	byte	0x0005			
CAL_DCO_8MHz	-	byte	0x0004			
CAL_BC1_12MHz	-	byte	0x0003			
CAL_DCO_12MHz	•	byte	0x0002			
CAL_BC1_16MHz	-	byte	0x0001			
CAL_DCO_16MHz	-	byte	0x0000			

brownout

The brownout circuit is implemented to provide the proper internal reset signal to the device during power on and power off.

digital I/O

There are three 8-bit I/O ports implemented—ports P1 through P3:

- All individual I/O bits are independently programmable.
- Any combination of input, output, and interrupt conditions is possible.
- Edge-selectable interrupt input capability for all eight bits of ports P1 and P2.
- Read/write access to port-control registers is supported by all instructions.
- Each I/O has an individually programmable pullup/pulldown resistor.

The MSP430F21x2 devices provides up to 24 total port I/O pins available externally. See the device pinout for more information.



watchdog timer + (WDT+)

The primary function of the WDT+ module is to perform a controlled system restart after a software problem occurs. If the selected time interval expires, a system reset is generated. If the watchdog function is not needed in an application, the module can be configured as an interval timer and can generate interrupts at selected time intervals.

ADC₁₀

The ADC10 module supports fast, 10-bit analog-to-digital conversions. The module implements a 10-bit SAR core, sample select control, reference generator, and data transfer controller (DTC), for automatic conversion result handling, allowing ADC samples to be converted and stored without any CPU intervention.

Comparator A+

The primary function of the comparator_A+ module is to support precision slope analog-to-digital conversions, battery-voltage supervision, and monitoring of external analog signals.

Timer0 A3

Timer0_A3 is a 16-bit timer/counter with three capture/compare registers. Timer0_A3 can support multiple capture/compares, PWM outputs, and interval timing. Timer0_A3 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

		TIMEF	RO_A3 SIGNAL	CONNECTION	ONS		
INPUT PIN	NUMBER	DEVICE	MODULE	MODULE	MODULE	OUTPUT PI	N NUMBER
28-PIN PW	32-PIN RHB	INPUT SIGNAL	INPUT NAME	BLOCK	OUTPUT SIGNAL	28-PIN PW	32-PIN RHB
21 - P1.0	21 - P1.0	TACLK	TACLK				
		ACLK	ACLK	_	NA		
		SMCLK	SMCLK	Timer		NA	
9 - P2.1	7 - P2.1	TAINCLK	INCLK				
22 - P1.1	22 - P1.1	TA0	CCI0A			22 - P1.1	22 - P1.1
10 - P2.2	8 - P2.2	TA0	CCI0B	0000	TA0	26 - P1.5	26 - P1.5
		DV _{SS}	GND	CCR0		10 - P2.2	8 - P2.2
		DV_CC	V _{CC}			ADC10 (internal)	ADC10 (internal)
23 - P1.2	23 - P1.2	TA1	CCI1A			23 - P1.2	23 - P1.2
		CAOUT (internal)	CCI1B	0004		27 - P1.6	27 - P1.6
		DV _{SS}	GND	CCR1	TA1	19 - P2.3	18 - P2.3
		DV _{CC}	V _{CC}			ADC10 (internal)	ADC10 (internal)
24 - P1.3	24 - P1.3	TA2	CCI2A			24 - P1.3	24 - P1.3
		ACLK (internal)	CCI2B	0000		28 - P1.7	28 - P1.7
		DV _{SS}	GND	CCR2	TA2	20 - P2.4	19 - P2.4
_		DV _{CC}	V _{CC}			ADC10 (internal)	ADC10 (internal)

Timer1_A2

Timer1_A2 is a 16-bit timer/counter with two capture/compare registers. Timer1_A2 can support multiple capture/compares, PWM outputs, and interval timing. Timer1_A2 also has extensive interrupt capabilities. Interrupts may be generated from the counter on overflow conditions and from each of the capture/compare registers.

		TIM	ER1_A2 SIGNAL	CONNECTION	S		
INPUT PIN	NUMBER	DEVICE INPUT	MODULE	MODULE	MODULE	OUTPUT P	N NUMBER
28-PIN PW	32-PIN RHB	SIGNAL	INPUT NAME	BLOCK	OUTPUT SIGNAL	28-PIN PW	32-PIN RHB
21 - P1.0	21 - P1.0	TACLK	TACLK				
		ACLK	ACLK	T	.		
		SMCLK	SMCLK	Timer	NA		
9 - P2.1	7 - P2.1	TAINCLK	INCLK				
22 - P1.1	22 - P1.1	TA0	CCI0A			17 - P3.6	15 - P3.6
17 - P3.6	15 - P3.6	TA0	CCI0B	0000	TAG		
		DV_SS	GND	CCR0	TA0		
		DV_CC	V _{CC}				
18 - P3.7	16 - P3.7	TA1	CCI1A			18 - P3.7	16 - P3.7
		CAOUT (internal)	CCI1B	0004	TA1		
		DV _{SS}	GND	CCR1			
		DV _{CC}	V _{CC}	1			

universal serial communications interface (USCI)

The USCI module is used for serial data communication. The USCI module supports synchronous communication protocols such as SPI (3 or 4 pin) and I2C, and asynchronous communication protocols such as UART, enhanced UART with automatic baudrate detection (LIN), and IrDA. Not all packages support the USCI functionality.

USCI A0 provides support for SPI (3 or 4 pin), UART, enhanced UART, and IrDA.

USCI B0 provides support for SPI (3 or 4 pin) and I2C.



peripheral file map

	PERIPHERALS WITH WORD ACCESS		
ADC10	ADC data transfer start address ADC memory ADC control register 1 ADC control register 0 ADC analog enable 0 ADC analog enable 1 ADC data transfer control register 1 ADC data transfer control register 0	ADC10SA ADC10MEM ADC10CTL1 ADC10CTL0 ADC10AE0 ADC10AE1 ADC10DTC1 ADC10DTC0	0x01BC 0x01B4 0x01B2 0x01B0 0x004A 0x004B 0x0049 0x0048
Timer0_A3	Capture/compare register Capture/compare register Capture/compare register Timer0_A3 register Capture/compare control Capture/compare control Capture/compare control Timer0_A3 control Timer0_A3 interrupt vector	TAOCCR2 TAOCCR1 TAOCCR0 TAOR TAOCCTL2 TAOCCTL1 TAOCCTL0 TAOCTL TAOCTL TAOIV	0x0176 0x0174 0x0172 0x0170 0x0166 0x0164 0x0162 0x0160 0x012E
Timer1_A2	Capture/compare register Capture/compare register Timer1_A2 register Capture/compare control Capture/compare control Timer1_A2 control Timer1_A2 interrupt vector	TA1CCR1 TA1CCR0 TA1R TA1CCTL1 TA1CCTL0 TA1CTL TA1CTL TA1IV	0x0194 0x0192 0x0190 0x0184 0x0182 0x0180 0x011E
Flash Memory	Flash control 3 Flash control 2 Flash control 1	FCTL3 FCTL2 FCTL1	0x012C 0x012A 0x0128
Watchdog Timer+	Watchdog/timer control	WDTCTL	0x0120
	PERIPHERALS WITH BYTE ACCESS	_	_
USCI_B0	USCI_B0 transmit buffer USCI_B0 receive buffer USCI_B0 status USCI B0 l2C Interrupt enable USCI_B0 bit rate control 1 USCI_B0 bit rate control 0 USCI_B0 control 1 USCI_B0 control 0 USCI_B0 control 0 USCI_B0 l2C slave address USCI_B0 l2C own address	UCBOTXBUF UCBORXBUF UCBOSTAT UCBOCIE UCBOBR1 UCBOBR0 UCBOCTL1 UCBOCTL0 UCBOSA UCBOOA	0x06F 0x06E 0x06D 0x06C 0x06B 0x06A 0x069 0x068 0x011A 0x0118
USCI_A0 (28-pin and 32-pin version only)	USCI_A0 transmit buffer USCI_A0 receive buffer USCI_A0 status USCI_A0 modulation control USCI_A0 baud rate control 1 USCI_A0 baud rate control 0 USCI_A0 control 1 USCI_A0 control 0 USCI_A0 IrDA receive control USCI_A0 auto baud rate control	UCAOTXBUF UCAORXBUF UCAOSTAT UCAOMCTL UCAOBR1 UCAOBR0 UCAOCTL1 UCAOCTL0 UCAOIRRCTL UCAOIRTCTL UCAOABCTL	0x0067 0x0066 0x0065 0x0064 0x0063 0x0062 0x0061 0x0060 0x005F 0x005E 0x005D
Comparator_A+	Comparator_A port disable Comparator_A control2 Comparator_A control1	CAPD CACTL2 CACTL1	0x005B 0x005A 0x0059



	PERIPHERALS WITH BYTE ACCESS (cont	tinued)	
Basic Clock System+	Basic clock system control 3 Basic clock system control 2 Basic clock system control 1 DCO clock frequency control	BCSCTL3 BCSCTL2 BCSCTL1 DCOCTL	0x0053 0x0058 0x0057 0x0056
Port P3	Port P3 resistor enable Port P3 selection Port P3 direction Port P3 output Port P3 input	P3REN P3SEL P3DIR P3OUT P3IN	0x0010 0x001B 0x001A 0x0019 0x0018
Port P2	Port P2 selection 2 Port P2 resistor enable Port P2 selection Port P2 interrupt enable Port P2 interrupt edge select Port P2 interrupt flag Port P2 direction Port P2 output Port P2 input	P2SEL2 P2REN P2SEL P2IE P2IES P2IFG P2DIR P2OUT P2IN	0x0042 0x002F 0x002E 0x002D 0x002C 0x002B 0x002A 0x0029 0x0028
Port P1	Port P1 selection 2 register Port P1 resistor enable Port P1 selection Port P1 interrupt enable Port P1 interrupt edge select Port P1 interrupt flag Port P1 direction Port P1 output Port P1 input	P1SEL2 P1REN P1SEL P1IE P1IES P1IFG P1DIR P1OUT P1IN	0x0041 0x0027 0x0026 0x0025 0x0024 0x0023 0x0022 0x0021 0x0020
Special Function	SFR interrupt flag 2 SFR interrupt flag 1 SFR interrupt enable 2 SFR interrupt enable 1	IFG2 IFG1 IE2 IE1	0x0003 0x0002 0x0001 0x0000



absolute maximum ratings (see Note 1)

NOTES: 1. Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- 2. All voltages referenced to V_{SS}. The JTAG fuse-blow voltage, V_{FB}, is allowed to exceed the absolute maximum rating. The voltage is applied to the TDI/TCLK pin when blowing the JTAG fuse.
- 3. Higher temperature may be applied during board soldering process according to the current JEDEC J-STD-020 specification with peak reflow temperatures not higher than classified on the device label on the shipping boxes or reels.

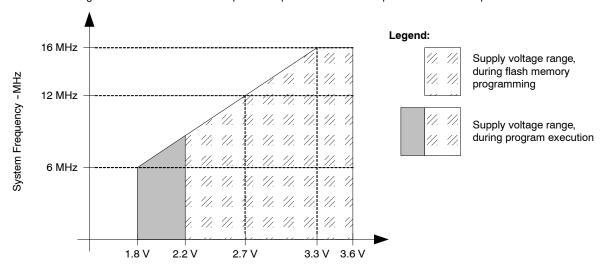
recommended operating conditions

PARAMETER		MIN	NOM	MAX	UNITS
Supply voltage during program execution, V _{CC}	AV _{CC} = DV _{CC} = V _{CC} (see Note 1)	1.8		3.6	V
Supply voltage during flash memory programming, V _{CC}	AV _{CC} = DV _{CC} = V _{CC} (see Note 1)	2.2		3.6	V
Supply voltage, V _{SS}	$AV_{SS} = DV_{SS} = V_{SS}$	0.0		0.0	V
Derating free-air temperature range, T _A	I version	-40		85	°C
Operating free-air temperature range, 1 _A	T version	-40		3.6 3.6 0.0	30
	V _{CC} = 1.8 V, Duty cycle = 50% ±10%	dc		6	
Processor frequency f _{SYSYTEM} (Maximum MCLK frequency) (see Notes 1, 2 and Figure 1)	V _{CC} = 2.7 V, Duty cycle = 50% ±10%	dc		12	MHz
	V _{CC} ≥ 3.3 V, Duty cycle = 50% ±10%	dc		16	

NOTES: 1. The MSP430 CPU is clocked directly with MCLK.

Both the high and low phase of MCLK must not exceed the pulse width of the specified maximum frequency.

2. Modules might have a different maximum input clock specification. See the specification of the respective module in this data sheet.



Supply Voltage -V NOTE: Minimum processor frequency is defined by system clock. Flash program or erase operations require a minimum V_{CC} of 2.2 V.

Figure 1. Operating Area



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

active mode supply current (into V_{CC}) excluding external current (see Notes 1 and 2)

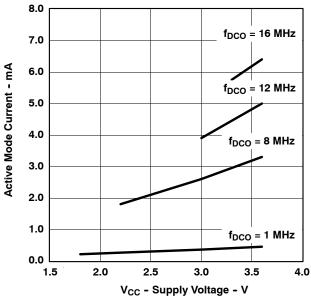
PA	RAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
I _{AM, 1MHz}	Active mode (AM)	f _{DCO} = f _{MCLK} = f _{SMCLK} = 1MHz, f _{ACLK} = 32,768Hz, Program executes from flash, BCSCTL1 = CALBC1 1MHZ,		2.2 V		200	250	μA
AIVI, TIVITIZ	current (1MHz)	DCOCTL = CALDCO_1MHZ, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0		3 V		300	200 250 300 350 160 260 2 5	,
lan ann	Active mode (AM)	f _{DCO} = f _{MCLK} = f _{SMCLK} = 1MHz, f _{ACLK} = 32,768Hz, Program executes in RAM,		2.2 V		160		uΑ
^I AM, 1MHz	current (1MHz)	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, CPUOFF = 0, SCG0 = 0, SCG1 = 0, OSCOFF = 0		3 V		260		
		$f_{MCLK} = f_{SMCLK} = f_{ACLK} = f_{ACLK} = 32,768 \text{Hz}/8 = 4,096 \text{Hz},$ $f_{DCO} = 0 \text{Hz},$ mode (AM) Program executes in flash,	-40°C to 85°C	2.2 V		2	5	
	Active mode (AM)		105°C	2.2 V			6	
I _{AM, 4kHz}	current (4kHz)	SELMx = 11, SELS = 1, DIVMx = DIVSx = DIVAx = 11,	-40°C to 85°C	0.14		3	7	μ A
		CPUOFF = 0, SCG0 = 1, SCG1 = 0, OSCOFF = 0	105°C	3 V			9	
		$f_{MCLK} = f_{SMCLK} = f_{DCO(0, 0)} \approx 100 \text{kHz},$	-40°C to 85°C	0.01/		60	85	
 .	Active mode (AM)	f _{ACLK} = 0Hz, Program executes in flash,	105°C	2.2 V			90	
IAM,100kHz	current (100kHz)	RSELx = 0, DCOx = 0, CPUOFF = 0, SCG0 = 0, SCG1 = 0,	-40°C to 85°C	3 V		72	95	μΑ
		OSCOFF = 1	105°C	υν			100	

NOTES: 1. All inputs are tied to 0 V or V_{CC} . Outputs do not source or sink any current.



^{2.} The currents are characterized with a Micro Crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.

typical characteristics - active mode supply current (into DV_{CC} + AV_{CC})



 $\label{eq:Vcc} V_{CC} \mbox{ - Supply Voltage - V}$ Figure 2. Active Mode Current vs $V_{CC},\,T_A=25^{\circ}C$

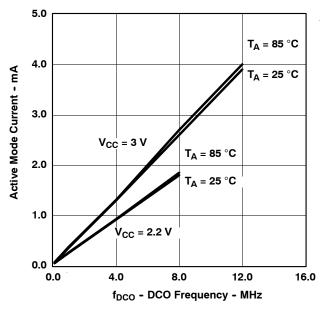


Figure 3. Active Mode Current vs DCO Frequency

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

low-power mode supply currents (into V_{CC}) excluding external current (see Notes 1 and 2)

PAI	RAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
		f _{MCLK} = 0 MHz,	-40°C to 85°C			32	45	
	Low-power mode 0	$f_{SMCLK} = f_{DCO} = 1$ MHz, $f_{ACLK} = 32,768$ Hz,	105°C	2.2 V			49	
I _{LPM0} , 1MHz	(LPM0) current, see Note 3	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ,	-40°C to 85°C			55	70	μΑ
		CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 0	105°C	3 V			2 45 49 5 70 74 0 27 31 1 42 46 8 16 20 0 25 31 7 1.2 6 2.3 8 6 9 1.2 6 2.8 8 7 6 0.7 8 0.7 9 2 5 7 0.8 4 2.1 6 6 1 0.5 1 0.5 1 0.5 1 0.5	
		f _{MCLK} = 0 MHz,	-40°C to 85°C			20	27	
	Low-power mode 0	$f_{SMCLK} = f_{DCO(0, 0)} \approx 100 \text{ kHz},$ $f_{ACLK} = 0\text{Hz},$	105°C	2.2 V			31	
ILPM0, 100kHz	(LPM0) current, see Note 3	RSELx = 0, $DCOx = 0$,	-40°C to 85°C			31	42	μΑ
		CPUOFF = 1, SCG0 = 0, SCG1 = 0, OSCOFF = 1	105°C	3 V		55 70 74 20 27 31 31 42 46 13 16 20 20 25 31 0.7 1.2 1.6 2.3 3 6 0.9 1.2 1.6 2.8 3 7 0.25 0.7 0.3 0.7 1.2 1.9 2 5 0.7 0.8 1.4 2.1		
		f _{MCLK} = f _{SMCLK} = 0 MHz, f _{DCO} = 1 MHz,	-40°C to 85°C	0.014		13	16	
	Low-power mode 2	f _{ACLK} = 32,768 Hz, BCSCTL1 = CALBC1 1MHZ,	105°C	2.2 V			20	
I _{LPM2}	(LPM2) current, see Note 4	DCOCTL = CALDCO_1MHZ,	-40°C to 85°C			20	25	μΑ
		CPUOFF = 1, SCG0 = 0, SCG1 = 1, OSCOFF = 0	105°C	3 V			0.7 1.2	
		T _{ACLK} = 32,768 Hz, CPUOFF = 1, SCG0 = 1, SCG1 = 1,	-40°C to 85°C			0.7	1.2	- μΑ
			85°C	2.2 V		1.6	2.3	
l.	Low-power mode 3		105°C			3	6	
ILPM3,LFXT1	(LPM3) current, see Note 4		-40°C to 85°C	3 V		0.9	1.2	
		OSCOFF = 0	85°C			1.6	2.8	
			105°C			3	55 70 74 20 27 31 31 42 46 13 16 20 20 25 31 0.7 1.2 1.6 2.3 3 6 0.9 1.2 1.6 2.8 3 7 0.25 0.7 0.3 0.7 1.2 1.9 2 5 0.7 0.8 1.4 2.1 2.5 6 0.1 0.5 0.1 0.5 0.8 1.5	
			-40°C			0.25	0.7	
			25°C			0.3	0.7	
	Low-power mode 3	f _{DCO} = f _{MCLK} = f _{SMCLK} = 0 MHz,	85°C	2.2 V		1.2	1.9	
I _{LPM3,VLO}	current, (LPM3)	f _{ACLK} from internal LF oscillator (VLO), CPUOFF = 1, SCG0 = 1, SCG1 = 1,	105°C			2	5	μΑ
,	see Note 4	OSCOFF = 0	-40°C to 85°C			0.7	0.8	
			85°C	3 V		1.4	2.1	
			105°C			2.5	6	
		f	-40°C			0.1	0.5	μΑ
	Low-power mode 4	$f_{DCO} = f_{MCLK} = f_{SMCLK} = 0 \text{ MHz},$ $f_{ACLK} = 0 \text{ Hz},$	25°C	2.2 V/		0.1	0.5	
I _{LPM4}	(LPM4) current, see Note 5	CPUOFF = 1, SCG0 = 1, SCG1 = 1,	85°C	3 V		0.8	1.5	
		OSCOFF = 1	105°C			2	4	

NOTES: 1. All inputs are tied to 0 V or V_{CC}. Outputs do not source or sink any current.

2. The currents are characterized with a Micro Crystal CC4V-T1A SMD crystal with a load capacitance of 9 pF. The internal and external load capacitance is chosen to closely match the required 9 pF.

- 3. Current for brownout and WDT clocked by SMCLK included.
- 4. Current for brownout and WDT clocked by ACLK included.
- 5. Current for brownout included.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

typical characteristics - LPM4 current

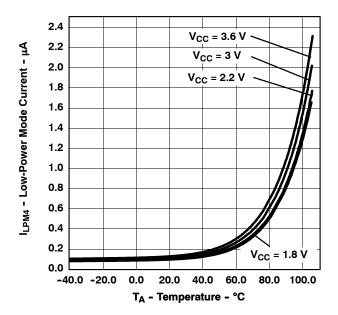


Figure 4. I_{LPM4} - LPM4 Current vs Temperature

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

Schmitt-trigger inputs - Ports P1, P2, P3, JTAG, RST/NMI, and XIN (see Note 1)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
				0.45		0.75	V_{CC}
V_{iT+}	Positive-going input threshold voltage		2.2 V	1.00		1.65	
	voltago		3 V	1.35		0.75 1.65 2.25 0.55 1.20 1.65 1.0 1.0	V
				0.25		0.55	V_{CC}
V _{IT-}	Negative-going input threshold voltage		2.2 V	0.55		1.20	
	vollago		3 V	0.75		0.75 1.65 2.25 0.55 1.20 1.65 1.0 1.0	V
V	Input voltage hysteresis		2.2 V	0.2		1.0	V
V _{hys}	V _{hys} (V _{IT+} - V _{IT-})		3 V	0.3		1.0	V
R _{Pull}	Pullup/pulldown resistor	For pullup: V _{IN} = V _{SS} ; For pulldown: V _{IN} = V _{CC}		20	35	50	kΩ
C _I	Input capacitance	V _{IN} = V _{SS} or V _{CC}			5		pF

NOTE 1: XIN only in bypass mode

inputs - Ports P1, P2

PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
t _(int) External interrupt timing	Port P1, P2: P1.x to P2.x, External trigger pulse width to set interrupt flag (see Note 2)	2.2 V/3 V	20			ns

NOTE 2: An external signal sets the interrupt flag every time the minimum interrupt pulse width $t_{(int)}$ is met. It may be set with trigger signals shorter than $t_{(int)}$.

leakage current - Ports P1, P2 and P3

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
I _{lka(Px x)}	High-impedance leakage current	See Notes 1 and 2	2.2 V/3 V			±50	nA

NOTES: 1. The leakage current is measured with V_{SS} or V_{CC} applied to the corresponding pin(s), unless otherwise noted.

2. The leakage of the digital port pins is measured individually. The port pin is selected for input and the pullup/pulldown resistor is disabled.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

outputs - Ports P1, P2 and P3

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP MAX	UNIT
		I _(OHmax) = -1.5 mA (see Notes 1)	2.2 V	V _{CC} -0.25	V_{CC}	
.,	High-level output	I _(OHmax) = -6 mA (see Notes 2)	2.2 V	V _{CC} -0.6	V _{CC}] ,,
V _{OH}	voltage	I _(OHmax) = -1.5 mA (see Notes 1)	3 V	V _{CC} -0.25	V_{CC}	٧
		I _(OHmax) = -6 mA (see Notes 2)	3 V	V _{CC} -0.6	V _{CC}	
		I _(OLmax) = 1.5 mA (see Notes 1)	2.2 V	V _{SS}	V _{SS} +0.25	
	Low-level output	I _(OLmax) = 6 mA (see Notes 2)	2.2 V	V _{SS}	V _{SS} +0.6	V
V _{OL}	voltage	I _(OLmax) = 1.5 mA (see Notes 1)	3 V	V _{SS}	V _{SS} +0.25]
		I _(OLmax) = 6 mA (see Notes 2)	3 V	V _{SS}	V _{SS} +0.6	

- NOTES: 1. The maximum total current, I_{OHmax} and I_{OLmax}, for all outputs combined, should not exceed ±12 mA to hold the maximum voltage drop specified.
 - 2. The maximum total current, I_{OHmax} and I_{OLmax}, for all outputs combined, should not exceed ±48 mA to hold the maximum voltage drop specified.

output frequency - Ports P1, P2 and P3

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
£_	Port output frequency	P1.4/SMCLK, $C_L = 20 \text{ pF}$, $R_L = 1 \text{ k}\Omega$	2.2 V			7.5	MHz
† _{Px.y}	(with load)	(see Note 1 and 2)	3 V			12	MHz
	Clock output frequency	P2.0/ACLK, P1.4/SMCLK, C _L = 20 pF	2.2 V			7.5	MHz
[†] Port_CLK	Clock output frequency	(see Note 2)	3 V			16	MHz

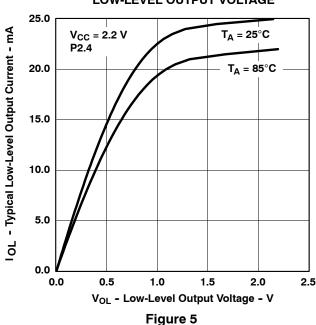
NOTES: 1. A resistive divider with $2 \times 0.5 \text{ k}\Omega$ between V_{CC} and V_{SS} is used as load. The output is connected to the center tap of the divider.

2. The output voltage reaches at least 10% and 90% V_{CC} at the specified toggle frequency.

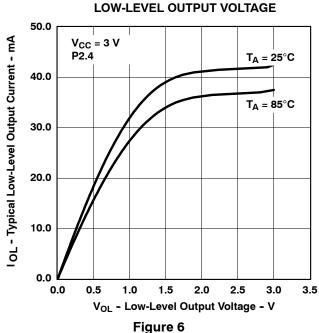
electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - outputs

TYPICAL LOW-LEVEL OUTPUT CURRENT LOW-LEVEL OUTPUT VOLTAGE



TYPICAL LOW-LEVEL OUTPUT CURRENT



TYPICAL HIGH-LEVEL OUTPUT CURRENT **HIGH-LEVEL OUTPUT VOLTAGE**

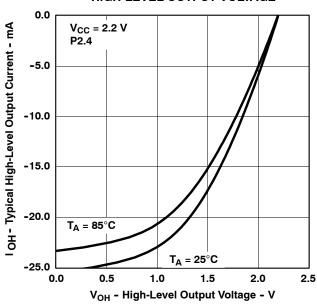
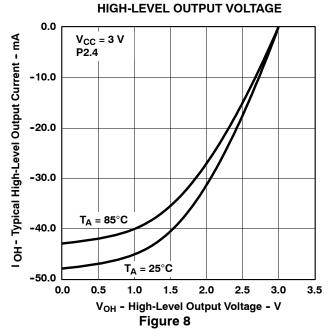


Figure 7

TYPICAL HIGH-LEVEL OUTPUT CURRENT



NOTE: One output loaded at a time.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

POR/brownout reset (BOR) (see Notes 1 and 2)

	PARAMETER	TEST CONDITIONS	V _{CC}			UNIT	
V _{CC(start)}	See Figure 9	$dV_{CC}/dt \le 3 \text{ V/s}$		0.7	7 × V _{(B_I}	T-)	V
V _(B_IT-)	See Figure 9 through Figure 11	dV _{CC} /dt ≤ 3 V/s				1.71	V
V _{hys(B_IT-)}	See Figure 9	dV _{CC} /dt ≤ 3 V/s		70	130	210	mV
t _{d(BOR)}	See Figure 9					2000	μS
t _(reset)	Pulse length needed at RST/NMI pin to accepted reset internally		2.2 V/3 V	2			μS

- NOTES: 1. The current consumption of the brownout module is already included in the I_{CC} current consumption data. The voltage level $V_{(B \mid T^-)} + V_{hys(B \mid T^-)}$ is $\leq 1.8V$.
 - 2. During power up, the CPU begins code execution following a period of $t_{d(BOR)}$ after $V_{CC} = V_{(B_IT-)} + V_{hys(B_IT-)}$. The default DCO settings must not be changed until $V_{CC} \ge V_{CC(min)}$, where $V_{CC(min)}$ is the minimum supply voltage for the desired operating frequency.

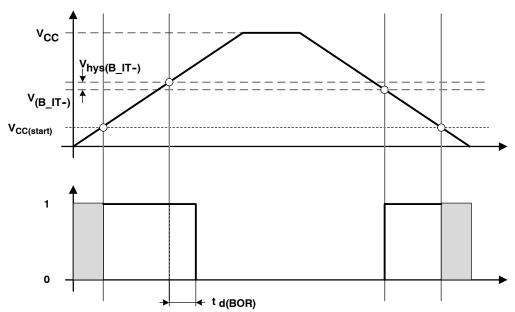


Figure 9. POR/Brownout Reset (BOR) vs Supply Voltage

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - POR/brownout reset (BOR)

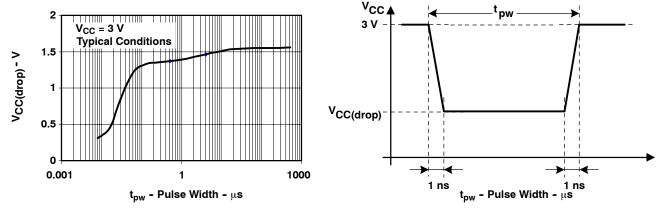


Figure 10. V_{CC(drop)} Level With a Square Voltage Drop to Generate a POR/Brownout Signal

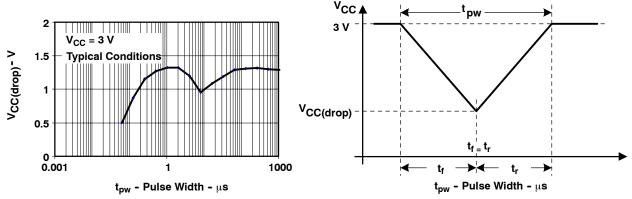


Figure 11. V_{CC(drop)} Level With a Triangle Voltage Drop to Generate a POR/Brownout Signal

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

main DCO characteristics

- All ranges selected by RSELx overlap with RSELx + 1; e.g., RSELx = 0 overlaps RSELx = 1, and RSELx = 14 overlaps RSELx = 15.
- DCO control bits DCOx have a step size as defined by parameter S_{DCO}.
- Modulation control bits MODx select how often f_{DCO(RSEL,DCO+1)} is used within the period of 32 DCOCLK cycles. The frequency f_{DCO(RSEL,DCO)} is used for the remaining cycles. The frequency is an average equal to:

$$f_{average} = \frac{32 \times f_{DCO(RSEL,DCO)} \times f_{DCO(RSEL,DCO+1)}}{MOD \times f_{DCO(RSEL,DCO)} + (32 - MOD) \times f_{DCO(RSEL,DCO+1)}}$$

DCO frequency

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
		RSELx < 14		1.8		3.6	٧
V_{CC}	Supply voltage range	RSELx = 14		2.2		3.6	٧
		RSELx = 15		3.0		3.6	٧
f _{DCO(0,0)}	DCO frequency (0, 0)	RSELx = 0, $DCOx = 0$, $MODx = 0$	2.2 V/3 V	0.06		0.14	MHz
f _{DCO(0,3)}	DCO frequency (0, 3)	RSELx = 0, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.07		0.17	MHz
f _{DCO(1,3)}	DCO frequency (1, 3)	RSELx = 1, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.10		0.20	MHz
f _{DCO(2,3)}	DCO frequency (2, 3)	RSELx = 2, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.14		0.28	MHz
f _{DCO(3,3)}	DCO frequency (3, 3)	RSELx = 3, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.20		0.40	MHz
f _{DCO(4,3)}	DCO frequency (4, 3)	RSELx = 4, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.28		0.54	MHz
f _{DCO(5,3)}	DCO frequency (5, 3)	RSELx = 5, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.39		0.77	MHz
f _{DCO(6,3)}	DCO frequency (6, 3)	RSELx = 6, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	0.54		1.06	MHz
f _{DCO(7,3)}	DCO frequency (7, 3)	RSELx = 7, DCOx = 3, MODx = 0	2.2 V/3 V	0.80		1.50	MHz
f _{DCO(8,3)}	DCO frequency (8, 3)	RSELx = 8, DCOx = 3, MODx = 0	2.2 V/3 V	1.10		2.10	MHz
f _{DCO(9,3)}	DCO frequency (9, 3)	RSELx = 9, $DCOx = 3$, $MODx = 0$	2.2 V/3 V	1.60		3.00	MHz
f _{DCO(10,3)}	DCO frequency (10, 3)	RSELx = 10, DCOx = 3, MODx = 0	2.2 V/3 V	2.50		4.30	MHz
f _{DCO(11,3)}	DCO frequency (11, 3)	RSELx = 11, DCOx = 3, MODx = 0	2.2 V/3 V	3.00		5.50	MHz
f _{DCO(12,3)}	DCO frequency (12, 3)	RSELx = 12, DCOx = 3, MODx = 0	2.2 V/3 V	4.30		7.30	MHz
f _{DCO(13,3)}	DCO frequency (13, 3)	RSELx = 13, DCOx = 3, MODx = 0	2.2 V/3 V	6.00		9.60	MHz
f _{DCO(14,3)}	DCO frequency (14, 3)	RSELx = 14, DCOx = 3, MODx = 0	2.2 V/3 V	8.60		13.9	MHz
f _{DCO(15,3)}	DCO frequency (15, 3)	RSELx = 15, DCOx = 3, MODx = 0	3 V	12.0		18.5	MHz
f _{DCO(15,7)}	DCO frequency (15, 7)	RSELx = 15, DCOx = 7, MODx = 0	3 V	16.0		26.0	MHz
S _{RSEL}	Frequency step between range RSEL and RSEL+1	$S_{RSEL} = f_{DCO(RSEL+1,DCO)}/f_{DCO(RSEL,DCO)}$	2.2 V/3 V			1.55	
S _{DCO}	Frequency step between tap DCO and DCO+1	$S_{DCO} = f_{DCO(RSEL,DCO+1)}/f_{DCO(RSEL,DCO)}$	2.2 V/3 V	1.05	1.08	1.12	ratio
Duty Cycle		Measured at P1.4/SMCLK	2.2 V/3 V	40	50	60	%

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

calibrated DCO frequencies - tolerance at calibration

	PARAMETER	TEST CONDITIONS	TA	Vcc	MIN	TYP	MAX	UNIT
Frequency to	olerance at calibration		25°C	3 V	-1	±0.2	+1	%
f _{CAL(1MHz)}	1-MHz calibration value	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, Gating time = 5 ms	25°C	3 V	0.990	1	1.010	MHz
f _{CAL(8MHz)}	8-MHz calibration value	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, Gating time = 5 ms	25°C	3 V	7.920	8	8.080	MHz
f _{CAL(12MHz)}	12-MHz calibration value	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, Gating time = 5 ms	25°C	3 V	11.88	12	12.12	MHz
f _{CAL(16MHz)}	16-MHz calibration value	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, Gating time = 2 ms	25°C	3 V	15.84	16	16.16	MHz

calibrated DCO frequencies - tolerance over temperature 0°C - +85°C

PARAMETER	TEST CONDITIONS	T _A	V _{CC}	MIN	TYP	MAX	UNIT
1-MHz tolerance over temperature		0°C to 85°C	3 V	-2.5	±0.5	+2.5	%
8-MHz tolerance over temperature		0°C to 85°C	3 V	-2.5	±1	+2.5	%
12-MHz tolerance over temperature		0°C to 85°C	3 V	-2.5	±1	+2.5	%
16-MHz tolerance over temperature		0°C to 85°C	3 V	-3	±2	+3	%
	BCSCTL1 = CALBC1 1MHZ,	0°C to 85°C	2.2 V	0.970	1	1.030	MHz
f _{CAL(1MHz)} 1-MHz calibration value	DCOCTL = CALDCO_1MHZ,		3 V	0.975	1	1.025	MHz
	Gating time: 5ms		3.6 V	0.970	1	1.030	MHz
	BCSCTL1 = CALBC1_8MHZ,	0°C to 85°C	2.2 V	7.760	8	8.400	MHz
f _{CAL(8MHz)} 8-MHz calibration value	DCOCTL = CALDCO_8MHZ,		3 V	7.800	8	8.200	MHz
	Gating time = 5 ms		3.6 V	7.600	8	8.240	MHz
	BCSCTL1 = CALBC1_12MHZ,		2.2 V	11.64	12	12.36	MHz
f _{CAL(12MHz)} 12-MHz calibration value	DCOCTL = CALDCO_12MHZ,	0°C to 85°C	3 V	11.64	12	12.36	MHz
	Gating time = 5 ms		3.6 V	11.64	12	12.36	MHz
f _{CAL (16MHz)} 16-MHz calibration value	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ,	0°C to 85°C	3 V	15.52	16	16.48	MHz
f _{CAL(16MHz)} 16-MHz calibration value	Gating time = 2 ms	0 0 10 85 0	3.6 V	15.00	16	16.48	MHz

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

calibrated DCO frequencies - tolerance over supply voltage V_{CC}

PARAMETER	TEST CONDITIONS	TA	V _{CC}	MIN	TYP	MAX	UNIT
1-MHz tolerance over V _{CC}		25°C	1.8 V to 3.6 V	-3	±2	+3	%
8-MHz tolerance over V _{CC}		25°C	1.8 V to 3.6 V	-3	±2	+3	%
12-MHz tolerance over V _{CC}		25°C	2.2 V to 3.6 V	-3	±2	+3	%
16-MHz tolerance over V _{CC}		25°C	3 V to 3.6 V	-6	±2	+3	%
f _{CAL(1MHz)} 1-MHz calibration value	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, Gating time = 5 ms	25°C	1.8 V to 3.6 V	0.970	1	1.030	MHz
f _{CAL(8MHz)} 8-MHz calibration value	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, Gating time = 5 ms	25°C	1.8 V to 3.6 V	7.760	8	8.240	MHz
f _{CAL(12MHz)} 12-MHz calibration value	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, Gating time = 5 ms	25°C	2.2 V to 3.6 V	11.64	12	12.36	MHz
f _{CAL(16MHz)} 16-MHz calibration value	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, Gating time = 2 ms	25°C	3 V to 3.6 V	15.00	16	16.48	MHz

calibrated DCO frequencies - overall tolerance

PARAMETER	TEST CONDITIONS	TA	V _{CC}	MIN	TYP	MAX	UNIT
1-MHz tolerance overall		-40°C to 105°C	1.8 V to 3.6 V	-5	±2	+5	%
8-MHz tolerance overall		-40°C to 105°C	1.8 V to 3.6 V	-5	±2	+5	%
12-MHz tolerance overall		-40°C to 105°C	2.2 V to 3.6 V	-5	±2	+5	%
16-MHz tolerance overall		-40°C to 105°C	3 V to 3.6 V	-6	±3	+6	%
f _{CAL(1MHz)} 1-MHz calibration value	BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ, Gating time = 5 ms	-40°C to 105°C	1.8 V to 3.6 V	0.950	1	1.050	MHz
f _{CAL(8MHz)} 8-MHz calibration value	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ, Gating time = 5 ms	-40°C to 105°C	1.8 V to 3.6 V	7.600	8	8.400	MHz
f _{CAL(12MHz)} 12-MHz calibration value	BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ, Gating time = 5 ms	-40°C to 105°C	2.2 V to 3.6 V	11.40	12	12.60	MHz
f _{CAL(16MHz)} 16-MHz calibration value	BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ, Gating time = 2 ms	-40°C to 105°C	3 V to 3.6 V	15.00	16	17.00	MHz

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - calibrated DCO frequency

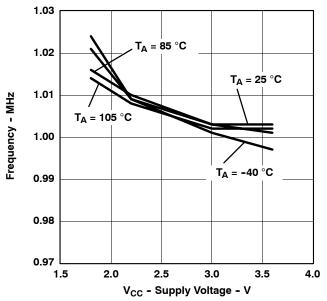


Figure 12. Calibrated 1 MHz Frequency vs V_{CC}



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

wake-up from lower power modes (LPM3/4)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN TYP	MAX	UNIT
^t DCO,LPM3/4		BCSCTL1 = CALBC1_1MHZ, DCOCTL = CALDCO_1MHZ	2.2 V/3 V		2	
	DCO clock wake-up time from LPM3/4 (see Note 1)	BCSCTL1 = CALBC1_8MHZ, DCOCTL = CALDCO_8MHZ	2.2 V/3 V			
		BCSCTL1 = CALBC1_12MHZ, DCOCTL = CALDCO_12MHZ	2.2 V/3 V		μS	
		BCSCTL1 = CALBC1_16MHZ, DCOCTL = CALDCO_16MHZ	3 V		1	
t _{CPU,LPM3/4}	CPU wake-up time from LPM3/4 (see Note 2)			1/f _{MCLK} + t _{Clock,LPM3/4}		

NOTES: 1. The DCO clock wake-up time is measured from the edge of an external wake-up signal (e.g., port interrupt) to the first clock edge observable externally on a clock pin (MCLK or SMCLK).

typical characteristics - DCO clock wake-up time from LPM3/4

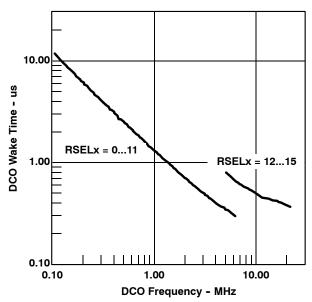


Figure 13. Clock Wake-Up Time From LPM3 vs DCO Frequency

^{2.} Parameter applicable only if DCOCLK is used for MCLK.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

DCO with external resistor R_{OSC} (see Note)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
f _{DCO,ROSC}	DCO output frequency with R _{OSC}	DCOR = 1, RSELx _ 4, DCOx = 3, MODx = 0,	2.2 V		1.8		MHz	
		T _A = 25°C	3 V		1.95			
D _t	Temperature drift	DCOR = 1, RSELx = 4, DCOx = 3, MODx = 0	2.2 V/3 V		±0.1		%/°C	
D _V	Drift with V _{CC}	DCOR = 1, RSELx = 4, DCOx = 3, MODx = 0	2.2 V/3 V		10		%/V	

NOTE: $R_{OSC} = 100 \text{ k}\Omega$. Metal film resistor, type 0257. 0.6 W with 1% tolerance and $T_K = \pm 50 \text{ ppm/}^{\circ}\text{C}$.

typical characteristics - DCO with external resistor Rosc

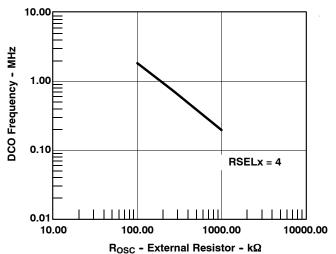


Figure 14. DCO Frequency vs R_{OSC}, V_{CC} = 2.2 V, T_A = 25°C

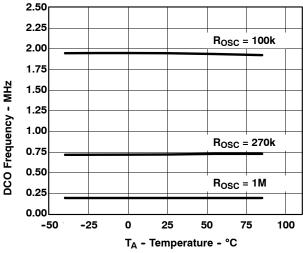
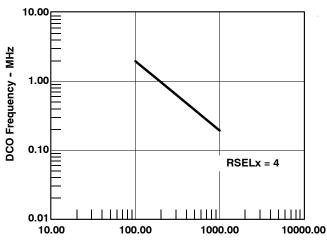


Figure 16. DCO Frequency vs Temperature, $V_{CC} = 3 \text{ V}$



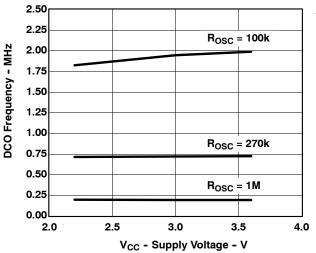


Figure 17. DCO Frequency vs V_{CC} , $T_A = 25^{\circ}C$



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

crystal oscillator, LFXT1, low frequency modes (see Note 4)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{LFXT1,LF}	LFXT1 oscillator crystal frequency, LF mode 0, 1	XTS = 0, LFXT1Sx = 0 or 1	1.8 V to 3.6 V		32,768		Hz
f _{LFXT1,LF,logic}	LFXT1 oscillator logic level square wave input frequency, LF mode	XTS = 0, XCAPx = 0, LFXT1Sx = 3	1.8 V to 3.6 V	10,000	32,768	50,000	Hz
OA _{LF}	Oscillation allowance for	$\begin{split} XTS &= 0, \ LFXT1Sx = 0, \\ f_{LFXT1,LF} &= 32,768 \ kHz, \\ C_{L,eff} &= 6 \ pF \end{split}$			500		10
	LF crystals	$XTS = 0$, $LFXT1Sx = 0$, $f_{LFXT1,LF} = 32,768$ kHz, $C_{L,eff} = 12$ pF			200	kΩ	
		XTS = 0, XCAPx = 0			1		
	Integrated effective load	XTS = 0, XCAPx = 1			5.5		_
$C_{L,eff}$	capacitance, LF mode (see Note 1)	XTS = 0, XCAPx = 2			8.5		pF
	(,	XTS = 0, XCAPx = 3			11		
Duty cycle	LF mode	XTS = 0, Measured at P2.0/ACLK, f _{LFXT1,LF} = 32,768Hz	2.2 V/3 V	30	50	70	%
f _{Fault,LF}	Oscillator fault frequency, LF mode (see Note 3)	XTS = 0, XCAPx = 0. LFXT1Sx = 3 (see Note 2)	2.2 V/3 V	10		10,000	Hz

NOTES: 1. Includes parasitic bond and package capacitance (approximately 2 pF per pin).

Since the PCB adds additional capacitance it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup the effective load capacitance should always match the specification of the used crystal.

- 2. Measured with logic level input frequency but also applies to operation with crystals.
- 3. Frequencies below the MIN specification set the fault flag, frequencies above the MAX specification do not set the fault flag, and frequencies in between might set the flag.
- 4. To improve EMI on the LFXT1 oscillator the following guidelines should be observed.
 - Keep the trace between the device and the crystal as short as possible.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
 - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.

internal very low power, low frequency oscillator (VLO)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{VLO}	VII O francisco	$T_A = -40^{\circ}C \text{ to } 85^{\circ}C$	2.2 V/3 V	4	12	20	kHz
	VLO frequency	T _A = 105°C	2.2 V/3 V			22	kHz
df _{VLO} /dT	VLO frequency temperature drift	See Note 1	2.2 V/3 V		0.5		%/°C
df_{VLO}/dV_{CC}	VLO frequency supply voltage drift	See Note 2	1.8V to 3.6V		4		%/V

NOTES: 1. Calculated using the box method:

I Version: (MAX(-40°C to 85°C) - MIN(-40°C to 85°C))/MIN(-40°C to 85°C)/(85°C - (-40°C))

T Version: (MAX(-40°C to 105_C) - MIN(-40°C to 105_C))/MIN(-40°C to 105_C)/(105_C - (-40_C))

2. Calculated using the box method: (MAX(1.8 V to 3.6 V) - MIN(1.8 V to 3.6 V))/MIN(1.8 V to 3.6 V)/(3.6 V - 1.8 V)



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

crystal oscillator, LFXT1, high frequency modes (see Note 5)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{LFXT1,HF0}	LFXT1 oscillator crystal frequency, HF mode 0	XTS = 1, XCAPx = 0, LFXT1Sx = 0	1.8 V to 3.6 V	0.4		1	MHz
f _{LFXT1,HF1}	LFXT1 oscillator crystal frequency, HF mode 1	XTS = 1, XCAPx = 0, LFXT1Sx = 1	1.8 V to 3.6 V	1		4	MHz
			1.8 V to 3.6 V	2		10	MHz
f _{LFXT1,HF2}	LFXT1 oscillator crystal frequency, HF mode 2	XTS = 1, XCAPx = 0, LFXT1Sx = 2	2.2 V to 3.6 V	2		12	MHz
	THE MIGGE Z		3 V to 3.6 V	2		16	MHz
			1.8 V to 3.6 V	0.4		10	MHz
f _{LFXT1,HF,logic}	LFXT1 oscillator logic level square wave input frequency, HF mode	XTS = 1, XCAPx = 0, LFXT1Sx = 3	2.2 V to 3.6 V	0.4		12	MHz
			3 V to 3.6 V	0.4		16	MHz
	Oscillation allowance for HF crystals (see Figure 18 and Figure 19)	$XTS = 1$, $XCAPx = 0$, $LFXT1Sx = 0$, $f_{LFXT1,HF} = 1$ MHz, $C_{L,eff} = 15$ pF			2700		Ω
OA _{HF}		$XTS = 1$, $XCAPx = 0$, $LFXT1Sx = 1$, $f_{LFXT1,HF} = 4$ MHz, $C_{L,eff} = 15$ pF			800		Ω
		$\begin{split} XTS &= 1, XCAPx = 0, LFXT1Sx = 2, \\ f_{LFXT1,HF} &= 16 MHz, C_{L,eff} = 15 pF \end{split}$			300		Ω
$C_{L,eff}$	Integrated effective load capacitance, HF mode (see Note 1)	XTS = 1, XCAPx = 0 (see Note 2)			1		pF
Duty cycle	HF mode	XTS = 1, XCAPx = 0, Measured at P2.0/ACLK, f _{LFXT1,HF} = 10 MHz	2.2 V/3 V	40	50	60	%
Duty cycle	Til Hiode	XTS = 1, XCAPx = 0, Measured at P2.0/ACLK, f _{LFXT1,HF} = 16 MHz	2.2 V/3 V	40	50	60	%
f _{Fault,HF}	Oscillator fault frequency, HF mode (see Note 4)	XTS = 1, XCAPx = 0, LFXT1Sx = 3 (see Notes 3)	2.2 V/3 V	30		300	kHz

NOTES: 1. Includes parasitic bond and package capacitance (approximately 2 pF per pin).

Since the PCB adds additional capacitance it is recommended to verify the correct load by measuring the ACLK frequency. For a correct setup the effective load capacitance should always match the specification of the used crystal.

- 2. Requires external capacitors at both terminals. Values are specified by crystal manufacturers.
- 3. Measured with logic level input frequency but also applies to operation with crystals.
- 4. Frequencies below the MIN specification set the fault flag, frequencies above the MAX specification do not set the fault flag, and frequencies in between might set the flag.
- 5. To improve EMI on the LFXT1 oscillator the following guidelines should be observed.
 - Keep the trace between the device and the crystal as short as possible.
 - Design a good ground plane around the oscillator pins.
 - Prevent crosstalk from other clock or data lines into oscillator pins XIN and XOUT.
 - Avoid running PCB traces underneath or adjacent to the XIN and XOUT pins.
 - Use assembly materials and praxis to avoid any parasitic load on the oscillator XIN and XOUT pins.
 - If conformal coating is used, ensure that it does not induce capacitive/resistive leakage between the oscillator pins.
 - Do not route the XOUT line to the JTAG header to support the serial programming adapter as shown in other documentation. This signal is no longer required for the serial programming adapter.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - LFXT1 oscillator in HF mode (XTS = 1)

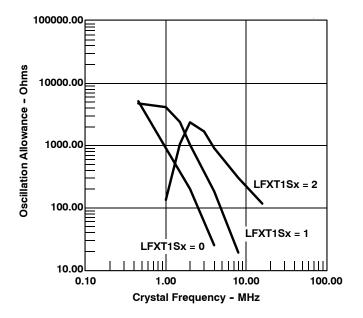


Figure 18. Oscillation Allowance vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25°C

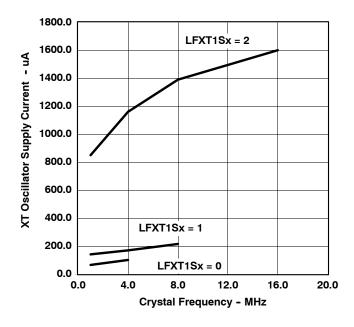


Figure 19. XT Oscillator Supply Current vs Crystal Frequency, $C_{L,eff}$ = 15 pF, T_A = 25 $^{\circ}$ C



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electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

Timer0_A3

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f	Timer0 A3 clock frequency	Internal: SMCLK, ACLK, External: TACLK, INCLK,	2.2 V			10	MHz
TTA	Tilliero_AS clock frequency	Duty cycle = 50% ± 10%	3 V			16	IVITZ
t _{TA,cap}	Timer0_A3, capture timing	TA0.0, TA0.1, TA0.2	2.2 V/3 V	20			ns

Timer1_A2

PARAMETER		TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{TB}	Timer1 A2 clock frequency	Internal: SMCLK, ACLK, External: TACLK, INCLK,	2.2 V			10	MHz
	Timer 1_A2 clock frequency	Duty cycle = 50% ± 10%	3 V			16	IVII IZ
t _{TB,cap}	Timer1_A2, capture timing	TA1.0, TA1.1	2.2 V/3 V	20			ns



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

USCI (UART mode)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP MAX	UNIT
f _{USCI}	USCI input clock frequency	Internal: SMCLK, ACLK, External: UCLK, Duty cycle = 50% ± 10%			fsystem	MHz
fmax, _{BITCLK}	Maximum BITCLK clock frequency (equals baudrate in MBaud) (see Note 1)		2.2V /3 V	2		MHz
	UART receive deglitch time		2.2 V	50	150	ns
τ _τ	(see Note 2)		3 V	50	100	ns

NOTES: 1. The DCO wake-up time must be considered in LPM3/4 for baudrates above 1 MHz.

2. Pulses on the UART receive input (UCxRX) shorter than the UART receive deglitch time are suppressed. To ensure that pulses are correctly recognized their width should exceed the maximum specification of the deglitch time.

USCI (SPI master mode) (see Figure 20 and Figure 21)

	PARAMETER	TEST CONDITIONS	V _{cc}	MIN	TYP MAX	UNIT
f _{USCI}	USCI input clock frequency	SMCLK, ACLK, Duty cycle = 50% ± 10%			f _{SYSTEM}	MHz
			2.2 V	110		ns
t _{SU,MI}	SOMI input data setup time		3 V	75		ns
			2.2 V	0		ns
t _{HD,MI}	SOMI input data hold time		3 V	0		ns
	0040	UCLK edge to SIMO valid,	2.2 V		30	ns
t _{VALID,MO}	SIMO output data valid time	C _L = 20 pF	3 V		20	ns

 $\text{NOTE:} \ \ f_{\text{UCxCLK}} = \frac{1}{2t_{\text{LO/HI}}} \text{ with } t_{\text{LO/HI}} \geq \\ \\ \text{max}(t_{\text{VALID,MO(USCI)}} + t_{\text{SU,SI(Slave)},} \\ \\ t_{\text{SU,MI(USCI)}} + t_{\text{VALID,SO(Slave)}}).$

For the slave parameters $t_{SU,SI(Slave)}$ and $t_{VALID,SO(Slave)}$, see the SPI parameters of the attached slave.

USCI (SPI slave mode) (see Figure 22 and Figure 23)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
t _{STE,LEAD}	STE lead time, STE low to clock		2.2 V/3 V		50		ns
t _{STE,LAG}	STE lag time, Last clock to STE high		2.2 V/3 V	10			ns
t _{STE,ACC}	STE access time, STE low to SOMI data out		2.2 V/3 V		50		ns
t _{STE,DIS}	STE disable time, STE high to SOMI high impedance		2.2 V/3 V		50		ns
			2.2 V	20			ns
t _{SU,SI}	SIMO input data setup time		3 V	15			ns
			2.2 V	10			ns
t _{HD,SI}	SIMO input data hold time		3 V	10			ns
		UCLK edge to SOMI valid,	2.2 V		75	110	ns
t _{VALID,} SO	SOMI output data valid time	C _L = 20 pF	3 V		50	75	ns

 $\text{NOTE: } f_{\text{UCxCLK}} = \frac{1}{2t_{\text{LO/HI}}} \text{ with } t_{\text{LO/HI}} \geq \text{max} \big(t_{\text{VALID,MO(Master)}} + t_{\text{SU,SI(USCI)}}, t_{\text{SU,MI(Master)}} + t_{\text{VALID,SO(USCI)}} \big).$

For the master's parameters $t_{SU,MI(Master)}$ and $t_{VALID,MO(Master)}$ refer to the SPI parameters of the attached master.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

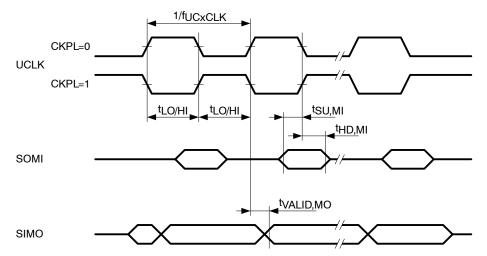


Figure 20. SPI Master Mode, CKPH = 0

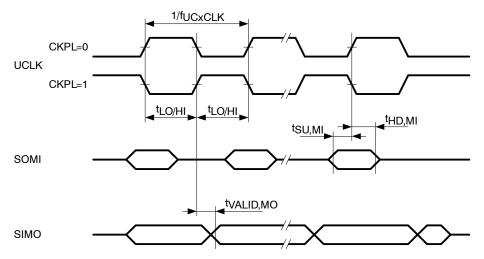


Figure 21. SPI Master Mode, CKPH = 1

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

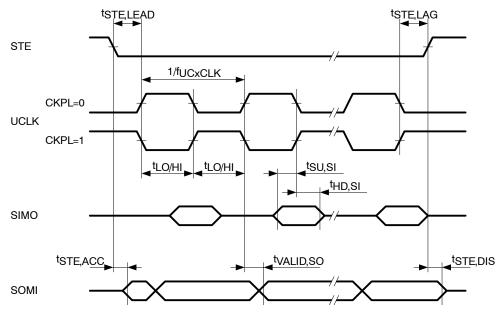


Figure 22. SPI Slave Mode, CKPH = 0

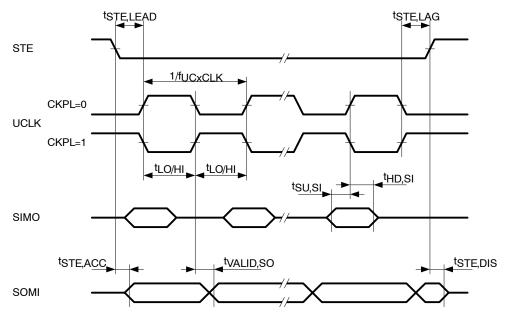


Figure 23. SPI Slave Mode, CKPH = 1

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

USCI (I2C mode) (see Figure 24)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
fusci	USCI input clock frequency	Internal: SMCLK, ACLK, External: UCLK, Duty Cycle = 50% ± 10%			fs	SYSTEM	MHz
f _{SCL}	SCL clock frequency		2.2 V/3 V	0		400	kHz
		f _{SCL} ≤ 100kHz	2.2 V/3 V	4.0			us
t _{HD,STA}	Hold time (repeated) start	f _{SCL} > 100kHz	2.2 V/3 V	0.6			us
	0	f _{SCL} ≤ 100kHz	2.2 V/3 V	4.7			us
t _{SU,STA}	Setup time for a repeated start	f _{SCL} > 100kHz	2.2 V/3 V	0.6			us
t _{HD,DAT}	Data hold time		2.2 V/3 V	0			ns
t _{SU,DAT}	Data setup time		2.2 V/3 V	250			ns
t _{SU,STO}	Setup time for stop		2.2 V/3 V	4.0			us
	Pulse width of spikes suppressed by		2.2 V	50	150	600	ns
t _{SP}	input filter		3 V	50	100	600	ns

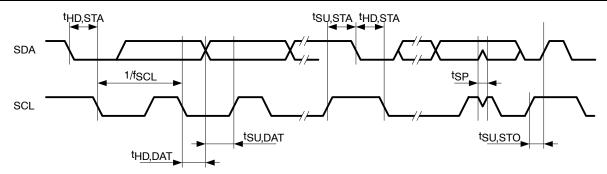


Figure 24. I2C Mode Timing

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

Comparator_A+ (see Note 1)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
1		CAON = 1, CARSEL = 0, CAREF = 0	2.2 V		25	40	μA
I _(DD)		CAON = 1, CANSEL = 0, CANEF = 0	3 V		45	60	μΑ
		CAON = 1, CARSEL = 0,	2.2 V		30	50	
(Refladder/Ref	fDiode)	CAREF = 1/2/3, No load at P1.0/CA0 and P1.1/CA1	3 V		45	71	μA
V _(IC)	Common-mode input voltage	CAON = 1	2.2 V/3 V	0		V _{CC} -1	V
V _(Ref025)	Voltage @ 0.25 V _{CC} node	PCA0 = 1, CARSEL = 1, CAREF = 1, No load at P1.0/CA0 and P1.1/CA1	2.2 V/3 V	0.23	0.24	0.25	
V _(Ref050)	Voltage @ 0.5V _{CC} node	PCA0 = 1, CARSEL = 1, CAREF = 2, No load at P1.0/CA0 and P1.1/CA1	2.2 V/3 V	0.47	0.48	0.5	
V	Can Figure 00 and Figure 00	PCA0 = 1, CARSEL = 1, CAREF = 3,	2.2 V	390	480	540	mV
V _(RefVT)	See Figure 28 and Figure 29	No load at P1.0/CA0 and P1.1/CA1, T _A = 85°C	3 V	400	490	550	IIIV
V _(offset)	Offset voltage	See Note 2	2.2 V/3 V	-30		30	mV
V _{hys}	Input hysteresis	CAON = 1	2.2 V/3 V	0	0.7	1.4	mV
		T _A = 25°C, Overdrive 10 mV,	2.2 V	80	165	300	
	Response time	Without filter: CAF = 0 (see Note 3, Figure 25 and Figure 26)	3 V	70	120	240	ns
t(response)	(low to high and high to low) (see Note 3)	T _A = 25°C, Overdrive 10 mV,	2.2 V	1.4	1.9	2.8	
		With filter: CAF = 1 (see Note 3, Figure 25 and Figure 26)	3 V	0.9	1.5	2.2	μS

NOTES: 1. The leakage current for the Comparator_A+ terminals is identical to $I_{lkg(Px,x)}$ specification.



^{2.} The input offset voltage can be cancelled by using the CAEX bit to invert the Comparator_A+ inputs on successive measurements. The two successive measurements are then summed together.

^{3.} Response time measured at P2.2/TA0.0/A2/CA4/CAOUT. If the Comparator_A+ is enabled a settling time of 60 ns (typical) is added to the response time.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

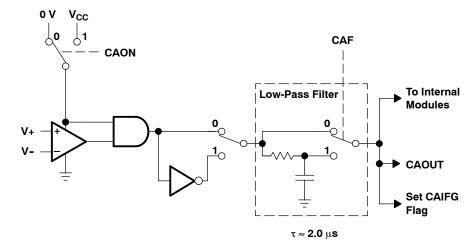


Figure 25. Block Diagram of Comparator_A+ Module

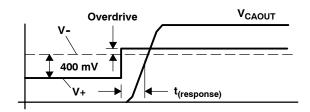


Figure 26. Overdrive Definition

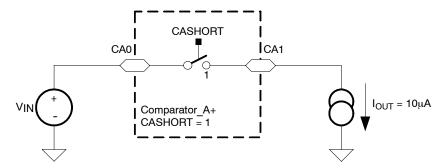


Figure 27. Comparator A+ Short Resistance Test Condition

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

typical characteristics - Comparator_A+

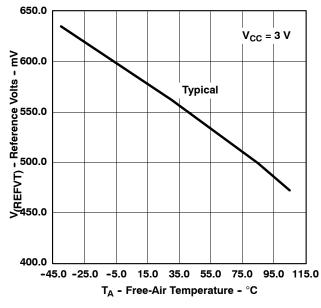


Figure 28. $V_{(RefVT)}$ vs Temperature, $V_{CC} = 3 V$

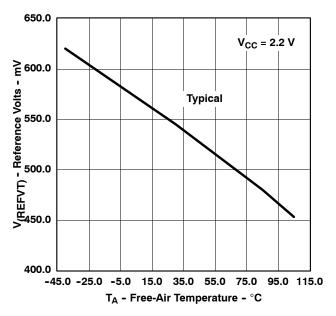


Figure 29. $V_{(RefVT)}$ vs Temperature, $V_{CC} = 2.2 \text{ V}$

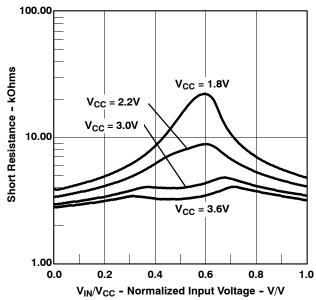


Figure 30. Short Resistance vs V_{IN}/V_{CC}

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

10-bit ADC, power supply and input range conditions (see Note 1)

	PARAMETER	TEST CONDITIONS	T _A	VCC	MIN	TYP	MAX	UNIT
V _{CC}	Analog supply voltage range	V _{SS} = 0 V			2.2		3.6	V
V _{Ax}	Analog input voltage range (see Note 2)	All Ax terminals, Analog inputs selected in ADC10AE register			0		V _{CC}	V
	ADC10 supply current	f _{ADC10CLK} = 5 MHz, ADC10ON = 1, REFON = 0	I: -40°C to 85°C	2.2 V		0.52	1.05	
I _{ADC10}	(see Note 3)	ADC10SHT0 = 1, ADC10SHT1 = 0, ADC10DIV = 0	T: -40°C to105°C	3 V		0.6	1.2	mA
	Reference supply	f _{ADC10CLK} = 5 MHz, ADC10ON = 0, REF2_5V = 0, REFON = 1, REFOUT = 0	I: -40°C to 85°C T: -40°C to105°C	2.2 V/3 V				mA
I _{REF+}	current, reference buffer disabled (see Note 4)	f _{ADC10CLK} = 5 MHz, ADC10ON = 0, REF2_5V = 1, REFON = 1, REFOUT = 0	I: -40°C to 85°C T: -40°C to105°C	3 V		0.25	0.4	mA
	Reference buffer supply current with	f _{ADC10CLK} = 5 MHz, ADC10ON = 0,	-40°C to 85°C	2.2 V/3 V		1.1	1.4	mA
I _{REFB,0}	ADC10SR = 0 (see Note 4)	REFON = 1, REF2_5V = 0, REFOUT = 1, ADC10SR = 0	105°C	2.2 V/3 V			1.8	mA
	Reference buffer supply current with	f _{ADC10CLK} = 5 MHz, ADC10ON = 0, REFON = 1,	-40°C to 85°C	2.2 V/3 V		0.5	0.7	mA
I _{REFB,1}	ADC10SR = 1 (see Note 4)	REF2_5V = 0, REFOUT = 1, ADC10SR = 1	105°C	2.2 V/3 V			0.8	mA
C _I	Input capacitance	Only one terminal Ax selected at a time	I: -40°C to 85°C T: -40°C to105°C				27	pF
R _I	Input MUX ON resistance	$0V \le V_{Ax} \le V_{CC}$	I: -40°C to 85°C T: -40°C to105°C	2.2 V/3 V			2000	Ω

NOTES: 1. The leakage current is defined in the leakage current table with Px.x/Ax parameter.



^{2.} The analog input voltage range must be within the selected reference voltage range V_{R+} to V_{R-} for valid conversion results.

^{3.} The internal reference supply current is not included in current consumption parameter I_{ADC10}.

^{4.} The internal reference current is supplied via terminal V_{CC}. Consumption is independent of the ADC10ON control bit, unless a conversion is active. The REFON bit enables the built-in reference to settle before starting an A/D conversion.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

10-bit ADC, built-in voltage reference

	PARAMETER	TEST CONDITION	ONS	TA	V _{CC}	MIN	TYP	MAX	UNIT
	Positive built-in	I _{VREF+} ≤ 1 mA, REF2_5V = 0)			2.2			
V _{CC,REF+}	reference analog supply	I _{VREF+} ≤ 0.5 mA, REF2_5V =	= 1			2.8			V
	voltage range	I _{VREF+} ≤ 1 mA, REF2_5V = 1				2.9			
V _{REF+}	Positive built-in	I _{VREF+} ≤ I _{VREF+} max, REF2_	5V = 0		2.2 V/ 3 V	1.41	1.5	1.59	V
112.1	reference voltage	I _{VREF+} ≤ I _{VREF+} max, REF2_	5V = 1		3 V	2.35	2.5	2.65	V
	Maximum V _{REF+} load				2.2 V			±0.5	^
I _{LD,VREF+}	current				3 V			±1	mA
	V land van detien	$I_{VREF+} = 500 \mu A \pm 100 \mu A$, Analog input voltage $V_{Ax} \approx 0$. REF2_5V = 0	75 V,		2.2 V/ 3 V			±2	LSB
	V _{REF+} load regulation	I_{VREF+} = 500 μA ± 100 μA, Analog input voltage V_{Ax} ≈ 1. REF2_5V = 1	25 V,		3 V			±2	LSB
	V _{REF+} load regulation	I _{VREF+} = 100 μA→900 μA,	ADC10SR = 0		3 V			400	
	response time	V _{Ax} ≈ 0.5 x V _{REF+} , Error of conversion result ≤ 1 LSB	ADC10SR = 1		3V			2000	ns
C _{VREF+}	Max. capacitance at pin V _{REF+} (see Note 1)	I _{VREF+} ≤ ±1 mA, REFON = 1, REFOUT = 1			2.2 V/ 3 V			100	pF
то.	Townson the coefficient	I _{VREF+ =} const. with 0 mA ≤ I _v	_{VREF+} ≤ 1 mA	-40°C to 85°C	2.2 V/ 3 V			±100	ppm/°C
TC _{REF+}	Temperature coefficient	(see Note 3)		85°C to 105°C	2.2 V/ 3 V			±110	ppm/°C
t _{REFON}	Settling time of internal reference voltage (see Note 2)	$I_{VREF+} = 0.5 \text{ mA, REF2_5V} = REFON = 0 \rightarrow 1$	0,		3.6 V			30	μs
		I _{VREF+ =} 0.5 mA, REF2 5V = 0,	ADC10SR = 0		2.2 V			1	
+	Settling time of	REFON = 1, REFBURST = 1	ADC10SR = 1		2.2 V			2.5	μS
t _{REFBURST}	reference buffer (see Note 2)		ADC10SR = 0		3 V			2	
		REFON = 1, REFBURST = 1	ADC10SR = 1		3 V			4.5	μS

NOTES: 1. The capacitance applied to the internal buffer operational amplifier, if switched to terminal P2.4/TA2/A4/V_{REF+}/V_{eREF+} (REFOUT = 1), must be limited; the reference buffer may become unstable, otherwise.



^{2.} The condition is that the error in a conversion started after t_{REFON} or t_{RefBuf} is less than ± 0.5 LSB.

^{3.} Calculated using the box method: ((MAX(V_{REF}(T)) - MIN(V_{REF}(T))) / MIN(V_{REF}(T)) / (T_{MAX} - T_{MIN})

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

10-bit ADC, external reference (see Note 1)

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP MAX	UNIT
.,	Positive external reference input voltage range (see Note 2)	V _{eREF+} > V _{eREF-} , SREF1 = 1, SREF0 = 0		1.4	V _C	
V _{eREF+}		$V_{eREF-} \le V_{eREF+} \le (V_{CC} - 0.15 \text{ V})$ SREF1 = 1, SREF0 = 1 (see Note 3)		1.4	3.0	
V _{eREF} -	Negative external reference input voltage range (see Note 4)	V _{eREF+} > V _{eREF-}		0	1.2	2 V
ΔV_{eREF}	Differential external reference input voltage range $\Delta V_{eREF} = V_{eREF+} - V_{eREF-}$	V _{eREF+} > V _{eREF-} (see Note 5)		1.4	V _C	; V
	Oldini in and a mond in la V	$0V \le V_{eREF+} \le V_{CC}$, SREF1 = 1, SREF0 = 0	2.2 V/3 V		±	
I _{VeREF+}	Static input current into V _{eREF+}	$0V \le V_{eREF+} \le (V_{CC} - 0.15 \text{ V}) \le 3 \text{ V},$ SREF1 = 1, SREF0 = 1 (see Note 3)	2.2 V/3 V		(μΑ
I _{VeREF} -	Static input current into VeREF-	0V ≤ V _{eREF} - ≤ V _{CC}	2.2 V/3 V		±'	μА

- NOTES: 1. The external reference is used during conversion to charge and discharge the capacitance array. The input capacitance, C_I, is also the dynamic load for an external reference during conversion. The dynamic impedance of the reference supply should follow the recommendations on analog-source impedance to allow the charge to settle for 10-bit accuracy.
 - 2. The accuracy limits the minimum positive external reference voltage. Lower reference voltage levels may be applied with reduced accuracy requirements.
 - 3. Under this condition the external reference is internally buffered. The reference buffer is active and requires the reference buffer supply current I_{REFB}. The current consumption can be limited to the sample and conversion period with REBURST = 1.
 - 4. The accuracy limits the maximum negative external reference voltage. Higher reference voltage levels may be applied with reduced accuracy requirements.
 - 5. The accuracy limits the minimum external differential reference voltage. Lower differential reference voltage levels may be applied with reduced accuracy requirements.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

10-bit ADC, timing parameters

	PARAMETER	TEST CONDIT	TIONS	V _{CC}	MIN	TYP	MAX	UNIT
	ADC10 input clock frequency	For specified performance of	ADC10SR = 0	2.2 V/3 V	0.45		6.3	N41.1-
fADC10CLK		ADC10 linearity A parameters 1	ADC10SR = 1	2.2 V/3 V	0.45		1.5	MHz
f _{ADC10OSC}	ADC10 built-in oscillator frequency	ADC10DIVx = 0, ADC f _{ADC10CLK} = f _{ADC10OSC}	2.2 V/3 V	3.7		6.3	MHz	
	Conversion time	ADC10 built-in oscillat ADC10SSELx = 0 fADC10CLK = fADC10OSC	•	2.2 V/3 V	2.06		3.51	μs
^t CONVERT	Conversion time		f _{ADC10CLK} from ACLK, MCLK or SMCLK: ADC10SSELx ≠ 0			13× DC10DIV f _{ADC10CL}		μS
t _{ADC10ON}	Turn on settling time of the ADC	See Note 1					100	ns

NOTE 1: The condition is that the error in a conversion started after t_{ADC100N} is less than ±0.5 LSB. The reference and input signals are already settled.

10-bit ADC, linearity parameters

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
El	Integral linearity error		2.2 V/3 V			±1	LSB
E _D	Differential linearity error		2.2 V/3 V			±1	LSB
Eo	Offset error	Source impedance R_S < 100 Ω	2.2 V/3 V			±1	LSB
		SREFx = 010, Unbuffered external reference; V _{eREF+ =} 1.5 V	2.2 V		±1.1	±2	LSB
		SREFx = 010, Unbuffered external reference; V _{eREF+} = 2.5 V	3 V		±1.1	±2	LSB
E _G	Gain error	SREFx = 011, Buffered external reference (see Note 2), $V_{eREF+} = 1.5 \text{ V}$	2.2 V		±1.1	±4	LSB
		SREFx = 011, Buffered external reference (see Note 2), $V_{eREF+} = 2.5 \text{ V}$	3 V		±1.1	±3	LSB
		SREFx = 010, Unbuffered external reference; V _{eREF+ =} 1.5 V	2.2 V		±2	±5	LSB
		SREFx = 010, Unbuffered external reference; V _{eREF+ =} 2.5 V	3 V		±2	±5	LSB
E _T	Total unadjusted error	SREFx = 011, Buffered external reference (see Note 2), $V_{eREF+} = 1.5 \text{ V}$	2.2 V		±2	±7	LSB
		SREFx = 011, Buffered external reference (see Note 2), $V_{eREF+} = 2.5 \text{ V}$	3 V		±2	±6	LSB

NOTE 2: The reference buffer's offset adds to the gain and total unadjusted error.

electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

10-bit ADC, temperature sensor and built-in V_{MID}

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT	
	Temperature sensor supply	REFON = 0, INCHx = 0Ah,	2.2 V		40	120	^	
ISENSOR	current (see Note 1)	ADC100N = 1, $T_A = 25^{\circ}C$	3 V		60	160	μΑ	
TC _{SENSOR}		ADC10ON = 1, INCHx = 0Ah (see Note 2)	2.2 V/3 V		3.55		mV/°C	
V _{Offset,Sensor}	Sensor offset voltage	ADC10ON = 1, INCHx = 0Ah (see Note 2)		-100		100	mV	
		Temperature sensor voltage at T _A = 105°C (T version only)	2.2 V/3 V	1265	1365	1465	mV	
V _{Sensor}	Sensor output voltage	Temperature sensor voltage at T _A = 85°C	2.2 V/3 V	1195	1295	1395	mV	
	(see Note 3)	Temperature sensor voltage at T _A = 25°C	2.2 V/3 V	985	1085	1185	.,	
		Temperature sensor voltage at T _A = 0°C	2.2 V/3 V	895	995	1095	mV	
t _{Sensor} (sample)	Sample time required if channel 10 is selected (see Note 4)	ADC10ON = 1, INCHx = 0Ah, Error of conversion result ≤ 1 LSB	2.2 V/3 V	30			μs	
	Current into divider at	150,000	2.2 V			NA		
I _{VMID}	channel11 (see Note 5)	ADC10ON = 1, INCHx = 0Bh,	3 V			NA	μΑ	
	M. alt talen at alconocal 44	ADC10ON = 1, INCHx = 0Bh,	2.2 V	1.06	1.1	1.14		
V_{MID}	V _{CC} divider at channel 11	V _{MID} is ≈0.5 x V _{CC}	3 V	1.46	1.5	1.54	V	
t _{VMID(sample)}	Sample time required if channel 11 is selected	ADC10ON = 1, INCHx = 0Bh,	2.2 V	1400			ns	
viviiD(sample)	(see Note 6)	Error of conversion result ≤ 1 LSB	3 V	1220			110	

NOTES: 1. The sensor current I_{SENSOR} is consumed if (ADC10ON = 1 and REFON = 1), or (ADC10ON = 1 and INCH = 0Ah and sample signal is high). When REFON = 1, I_{SENSOR} is included in I_{REF+}. When REFON = 0, I_{SENSOR} applies during conversion of the temperature sensor input (INCH = 0Ah).

2. The following formula can be used to calculate the temperature sensor output voltage:

$$\begin{split} &V_{Sensor,typ} = \overset{-}{TC}_{Sensor} \left(\ 273 + T \ [^{\circ}C] \ \right) + V_{Offset,sensor} \left[mV \right] \text{ or } \\ &V_{Sensor,typ} = TC_{Sensor} T \ [^{\circ}C] + V_{Sensor} (T_A = 0^{\circ}C) \ [mV] \end{split}$$

3. Results based on characterization and/or production test, not TC_{Sensor} or V_{Offset,sensor}.

4. The typical equivalent impedance of the sensor is 51 kΩ. The sample time required includes the sensor-on time t_{SENSOR(on)}.

5. No additional current is needed. The $V_{\mbox{\scriptsize MID}}$ is used during sampling.

6. The on-time t_{VMID(on)} is included in the sampling time t_{VMID(sample)}; no additional on time is needed.



electrical characteristics over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (continued)

flash memory

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
V _{CC(PGM/} ERASE)	Program and erase supply voltage			2.2		3.6	٧
f_{FTG}	Flash timing generator frequency			257		476	kHz
I _{PGM}	Supply current from V _{CC} during program		2.2 V/3.6 V		1	5	mA
I _{ERASE}	Supply current from V _{CC} during erase		2.2 V/3.6 V		1	7	mA
t _{CPT}	Cumulative program time (see Note 1)		2.2 V/3.6 V			10	ms
t _{CMErase}	Cumulative mass erase time		2.2 V/3.6 V	20			ms
	Program/erase endurance			10 ⁴	10 ⁵		cycles
t _{Retention}	Data retention duration	$T_J = 25^{\circ}C$		100			years
t _{Word}	Word or byte program time				30		t _{FTG}
t _{Block, 0}	Block program time for first byte or word				25		t _{FTG}
t _{Block, 1-63}	Block program time for each additional byte or word	O Note O			18		t _{FTG}
t _{Block, End}	Block program end-sequence wait time	See Note 2		6			t _{FTG}
t _{Mass Erase}	Mass erase time				10593		t _{FTG}
t _{Seg Erase}	Segment erase time				4819		t _{FTG}

NOTES: 1. The cumulative program time must not be exceeded when writing to a 64-byte flash block. This parameter applies to all programming methods: individual word/byte write and block write modes.

RAM

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{(RAMh)}$	RAM retention supply voltage (see Note)	CPU halted	1.6			V

NOTE: This parameter defines the minimum supply voltage V_{CC} when the data in RAM remains unchanged. No program execution should happen during this supply voltage condition.



^{2.} These values are hardwired into the Flash Controller's state machine ($t_{FTG} = 1/f_{FTG}$).

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JTAG and Spy-Bi-Wire interface

	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	TYP	MAX	UNIT
f _{SBW}	Spy-Bi-Wire input frequency		2.2 V/3 V	0		20	MHz
t _{SBW,Low}	Spy-Bi-Wire low clock pulse length		2.2 V/3 V	0.025		15	us
t _{SBW,En}	Spy-Bi-Wire enable time, TEST high to acceptance of first clock edge (see Note 1)		2.2 V/3 V			1	us
t _{SBW,Ret}	Spy-Bi-Wire return to normal operation time		2.2 V/3 V	15		100	us
	TOK insul fragues (see Note 0)		2.2 V	0		5	MHz
f _{TCK}	TCK input frequency (see Note 2)		3 V	0		10	MHz
R _{Internal}	Internal pulldown resistance on TEST		2.2 V/3 V	25	60	90	kΩ

- NOTES: 1. Tools accessing the Spy-Bi-Wire interface need to wait for the maximum t_{SBW,En} time after pulling the TEST/SBWCLK pin high before applying the first SBWCLK clock edge.
 - 2. f_{TCK} may be restricted to meet the timing requirements of the module selected.

JTAG fuse (see Note)

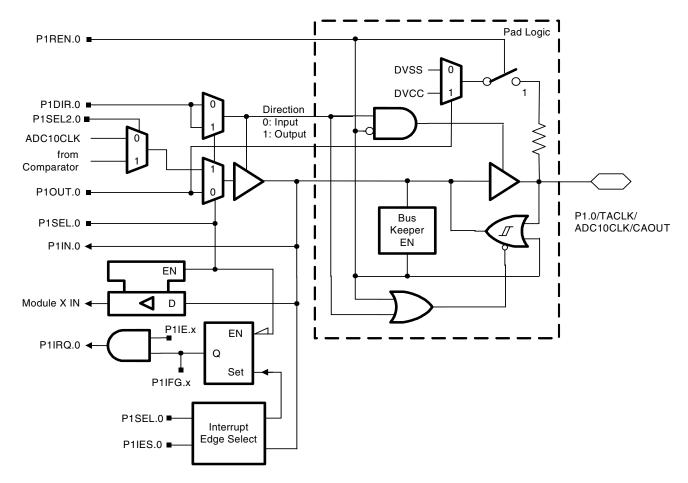
	PARAMETER	TEST CONDITIONS	V _{CC}	MIN	NOM	MAX	UNIT
V _{CC(FB)}	Supply voltage during fuse-blow condition	T _A = 25°C		2.5			V
V_{FB}	Voltage level on TEST for fuse-blow (F versions)			6		7	V
I _{FB}	Supply current into TDI/TCLK during fuse blow					100	mA
t _{FB}	Time to blow fuse					1	ms

NOTE: Once the fuse is blown, no further access to the MSP430 JTAG/Test and emulation features is possible. The JTAG block is switched to bypass mode.



APPLICATION INFORMATION

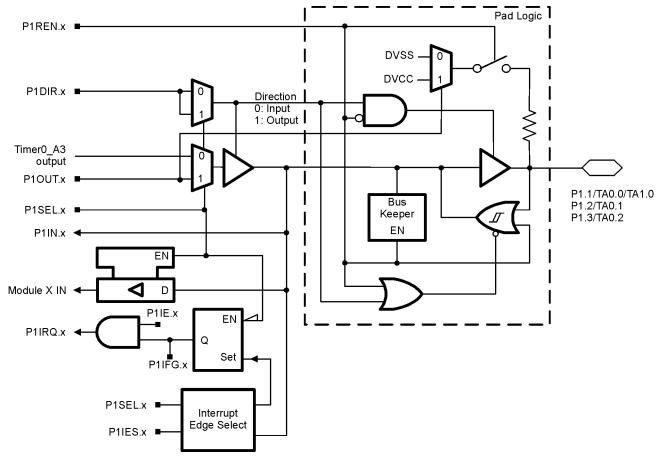
Port P1 pin schematic: P1.0, input/output with Schmitt trigger



Port P1 (P1.0) pin functions

PIN NAME (P1.x)		FUNCTION	CONTROL BITS / SIGNALS				
PIN NAME (P1.X)	Х	FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x		
P1.0/TACLK/	0	P1.0 (I/O)	I: 0, O: 1	0	0		
ADC10CLK/CAOUT		Timer0_A3.TACLK, Timer1_A2.TACLK	0	1	0		
		ADC10CLK	1	1	0		
		CAOUT	1	1	1		

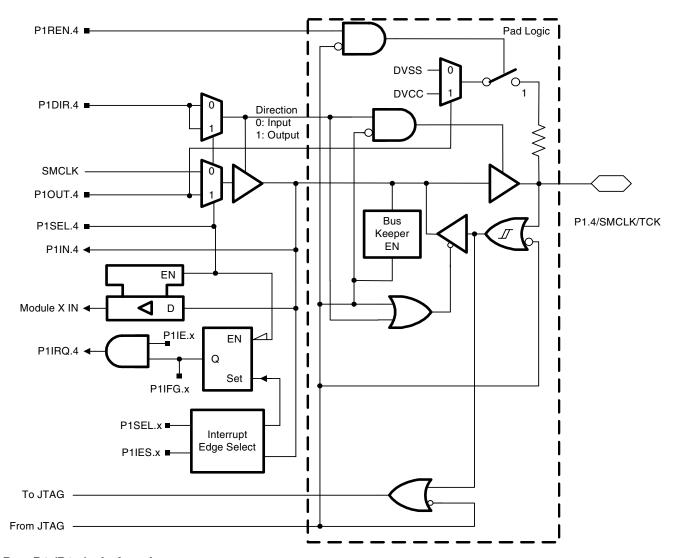
Port P1 pin schematic: P1.1 to P1.3, input/output with Schmitt trigger



Port P1 (P1.1 to P1.3) pin functions

DIN NAME (D4 v)		FUNCTION	CONT	ROL BITS / SIG	NALS
PIN NAME (P1.x)	Х	FUNCTION	P1DIR.x	P1SEL.x	P1SEL2.x
P1.1/TA0.0/TA1.0	1	P1.1 (I/O)	l: 0; O: 1	0	0
		Timer0_A3.CCl0A, Timer1_A2.CCl0A	0	1	0
		Timer0_A3.TA0	1	1	0
P1.2/TA0.1	2	P1.2 (I/O)	l: 0; O: 1	0	0
		Timer0_A3.CCI0A	0	1	0
		Timer0_A3.TA0	1	1	0
P1.3/TA0.2	3	P1.3 (I/O)	I: 0; O: 1	0	0
		Timer0_A3.CCI0A	0	1	0
		Timer0_A3.TA0	1	1	0

Port P1 pin schematic: P1.4



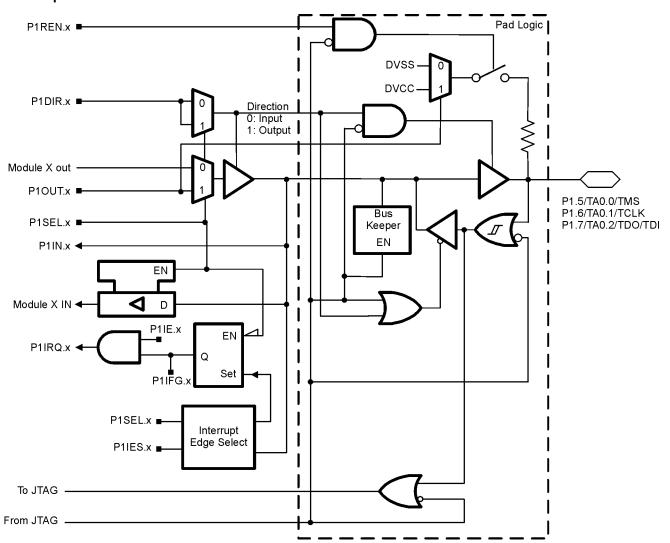
Port P1 (P1.4) pin functions

			CONTROL BITS / SIGNALS				
PIN NAME (P1.x)	x	FUNCTION	P1DIR.x	P1SEL.x P1SEL2.x = 0	JTAG Mode		
P1.4/SMCLK/TCK	4	P1.4 (I/O)	I: 0; O: 1	0	0		
		SMCLK	1	1	0		
		TCK (see Note 1)	Х	Х	1		

NOTES: 1. In JTAG Mode the internal pullup/pulldown resistors are disabled.

2. X: Don't care.

Port P1 pin schematic: P1.5 to P1.7



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

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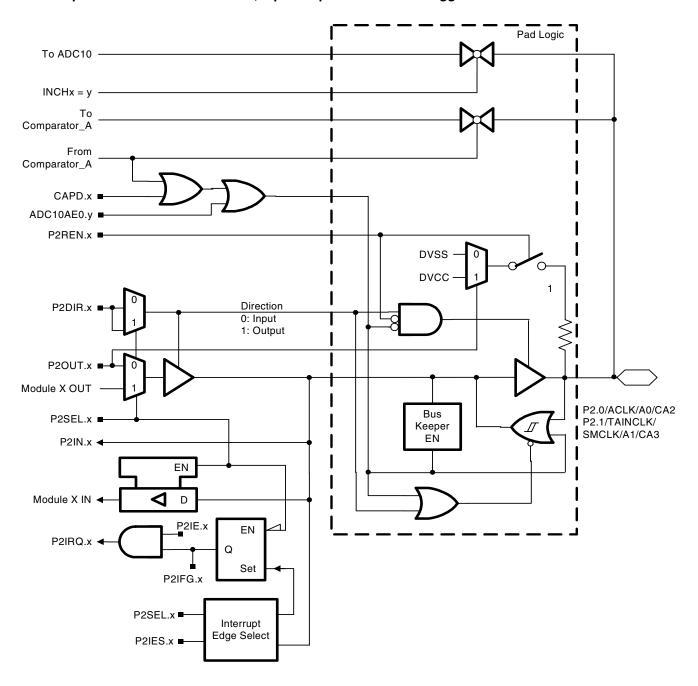
Port P1 (P1.5 to P1.7) pin functions

			CONT	ROL BITS / SIG	NALS
PIN NAME (P1.x)	x	FUNCTION	P1DIR.x	P1SEL.x P1SEL2.x = 0	JTAG Mode
P1.5/TA0.0/TMS	5	P1.5 (I/O)	I: 0; O: 1	0	0
		Timer0_A3.TA0	1	1	0
		TMS (see Note 1)	Х	X	1
P1.6/TA0.1/	6	P1.6 (I/O)	I: 0; O: 1	0	0
TDI/TCLK		Timer0_A3.TA1	1	1	0
		Timer0_A3.CCI0B	0	1	0
		TDI/TCLK (see Note 1)	Х	Х	1
P1.7/TA0.2/TDO/TDI	7	P1.6 (I/O)	I: 0; O: 1	0	0
		Timer0_A3.TA2	1	1	0
		TDO/TDI (see Note 1)	Х	Х	1

NOTES: 1. In JTAG Mode the internal pullup/pulldown resistors are disabled.

2. X: Don't care.

Port P2 pin schematic: P2.0 and P2.1, input/output with Schmitt trigger



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

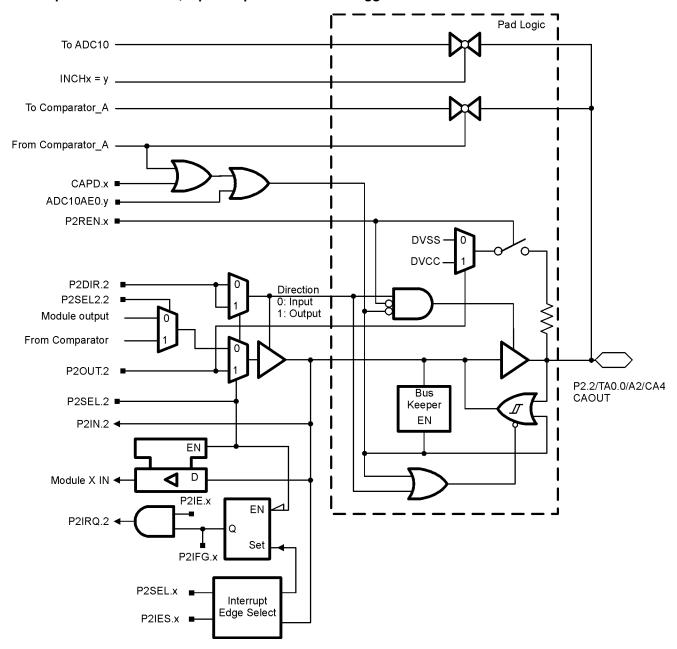
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Port P2 (P2.0 and P2.1) pin functions

				CONTROL E	BITS / SIGNALS	
PIN NAME (P2.x)	x	FUNCTION	ADC10AE0.y	CAPD.x	P2DIR.x	P2SEL.x P2SEL2.x = 0
P2.0/ACLK/A0/CA2	0	P2.0 (I/O)	0	0	I: 0; O: 1	0
		ACLK	0	0	1	1
		A0	1	0	Х	Х
		CA2	0	1	Х	Х
P2.1/TAINCLK/	1	P2.1 (I/O)	0	0	I: 0; O: 1	0
SMCLK/A1/CA3		Timer0_A3.TAINCLK, Timer1_A2.TAINCLK	0	0	0	1
		SMCLK	0	0	1	1
		A1	1	0	Х	Х
		CA3	0	1	Х	Х

NOTE: X: Don't care.

Port P2 pin schematic: P2.2, input/output with Schmitt trigger



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

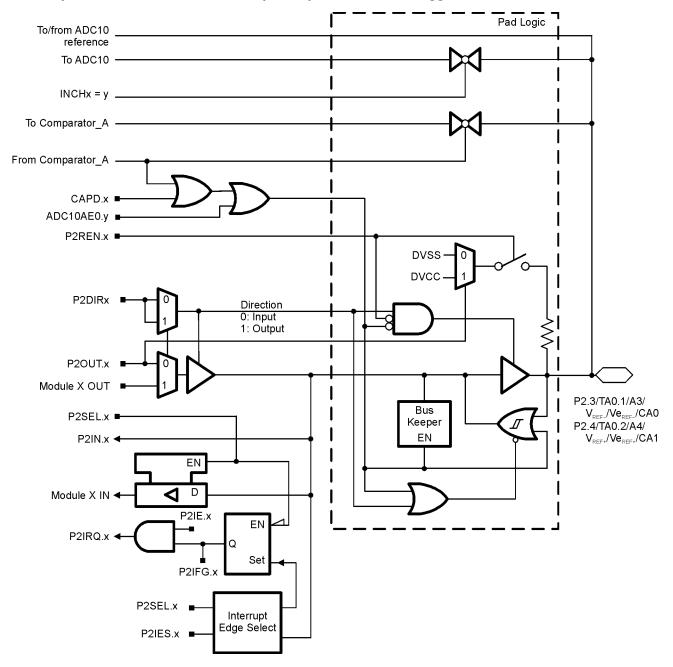
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Port P2 (P2.2) pin functions

DIN NAME (DO v)		FUNCTION	CONTROL BITS / SIGNALS					
PIN NAME (P2.x)	X	FUNCTION	ADC10AE0.x	CAPD.x	P2DIR.x	P2SEL.x	P2SEL2.x	
P2.2/TA0.0/A2/CA4/ CAOUT	2	P2.0 (I/O)	0	0	I: 0; O: 1	0	0	
		Timer0_A3.TA0	0	0	1	1	0	
		Timer0_A3.CCI0B	0	0	0	1	0	
		A2	1	0	Х	Х	Х	
		CA4	0	1	Х	X	Х	
		CAOUT	0	0	1	1	1	

NOTE: X: Don't care.

Port P2 pin schematic: P2.3 and P2.4, input/output with Schmitt trigger



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

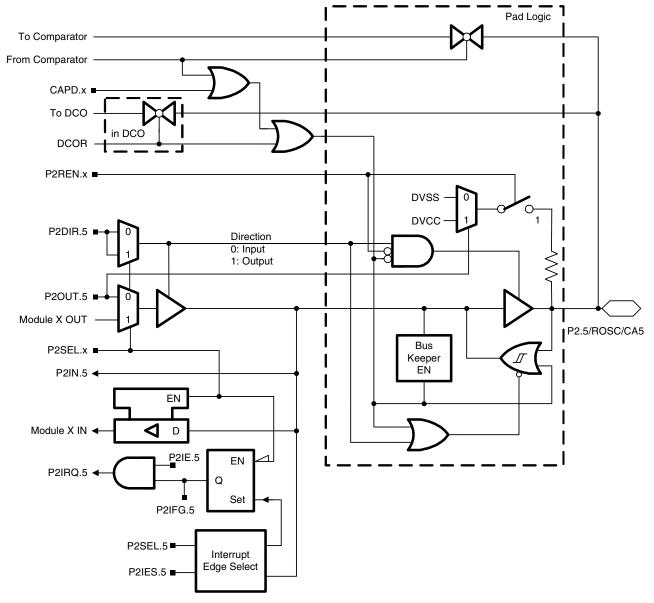
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Port P2 (P2.3 and P2.4) pin functions

				CONTROL E	SITS / SIGNALS	
PIN NAME (P2.x)	x	FUNCTION	ADC10AE0.y	CAPD.x	P2DIR.x	P2SEL.x P2SEL2.x = 0
P2.3/TA0.1/A3/ V _{Ref-} /Ve _{Ref-} /CA0	3	P2.3 (I/O)	0	0	I: 0; O: 1	0
		Timer0_A3.TA1	0	0	1	1
		A3/V _{Ref-} /Ve _{Ref-}	1	0	Х	X
		CA0	0	1	Х	X
P2.4/TA0.2/A4/	4	P2.4 (I/O)	0	0	I: 0; O: 1	0
V _{Ref+} /Ve _{Ref+} /CA1		Timer0_A3.TA2	0	0	1	1
		A4/V _{Ref+} /Ve _{Ref+}	1	0	X	Х
		CA1	0	1	Х	X

NOTE: X: Don't care.

Port P2 pin schematic: P2.5, input/output with Schmitt trigger



Port P2 (P2.5) pin functions

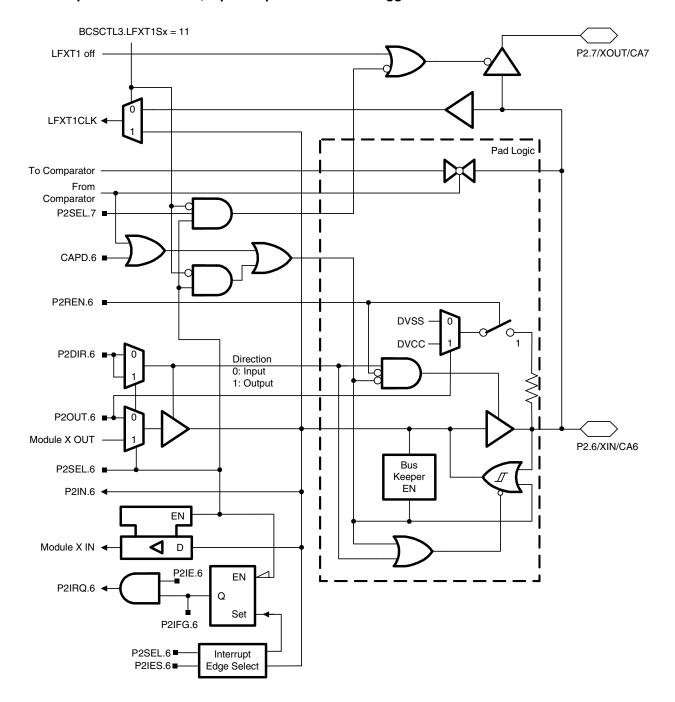
			CONTROL BITS / SIGNALS					
PIN NAME (P2.x)	x	FUNCTION	CAPD.5	DCOR	P2DIR.5	P2SEL.5 P2SEL2.x = 0		
P2.5/R _{OSC} /CA5	5	P2.5 (I/O)	0	0	I: 0, O: 1	0		
		R _{OSC}	0	1	X	Х		
		DV _{SS}	0	0	1	1		
		CA5 (see Note 2)	1	0	Х	Х		

NOTES: 1. X: Don't care.

2. Setting the CAPD.x bit disables the output driver as well as the input to prevent parasitic cross currents when applying analog signals. Selecting the CAx input to the comparator multiplexer with the P2CAx bits automatically disables the input buffer for that pin, regardless of the state of the associated CAPD.x bit.



Port P2 pin schematic: P2.6, input/output with Schmitt trigger



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

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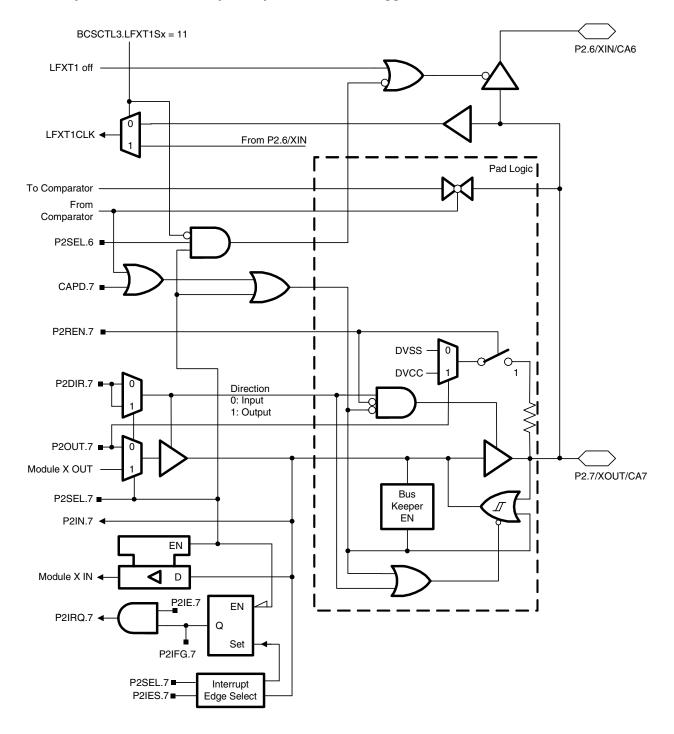
Port P2.6 pin functions

			CONT	ROL BITS / SIG	NALS
Pin Name (P2.x)	x	FUNCTION	CAPD.6	P2DIR.6	P2SEL.6 P2SEL2.x = 0
P2.6/XIN/CA6	6	P2.6 (I/O)	0	I: 0; O: 1	0
		XIN (default)	X	1	1
		CA6 (see Note 2)	1	Х	0

NOTES: 1. X: Don't care.

2. Setting the CAPD.x bit disables the output driver as well as the input to prevent parasitic cross currents when applying analog signals. Selecting the CAx input to the comparator multiplexer with the P2CAx bits automatically disables the input buffer for that pin, regardless of the state of the associated CAPD.x bit.

Port P2 pin schematic: P2.7, input/output with Schmitt trigger



MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

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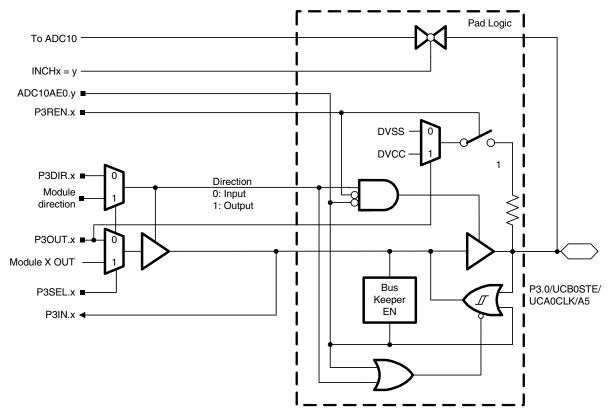
Port P2.7 pin functions

			CONT	ROL BITS / SIG	NALS
PIN NAME (P2.x)	x	FUNCTION	CAPD.7	P2DIR.7	P2SEL.7 P2SEL2.x = 0
P2.7/XOUT/CA7	7	P2.7 (I/O)	0	I: 0, O: 1	0
		XOUT (default)	Х	1	1
		CA7 (see Note 2)	1	X	0

NOTES: 1. X: Don't care.

2. Setting the CAPD.x bit disables the output driver as well as the input to prevent parasitic cross currents when applying analog signals. Selecting the CAx input to the comparator multiplexer with the P2CAx bits automatically disables the input buffer for that pin, regardless of the state of the associated CAPD.x bit.

Port P3 pin schematic: P3.0, input/output with Schmitt trigger



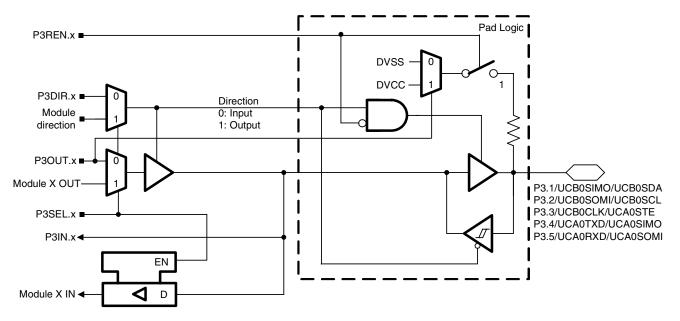
Port P3.0 pin functions

			CONTROL BITS / SIGNALS				
PIN NAME (P3.x)	х	FUNCTION	ADC10AE0.y	P3DIR.x	P3SEL.x P3SEL2.x = 0		
P3.0/UCB0STE/	0	P3.0 (I/O)	0	I: 0; O: 1	0		
UCA0CLK/A5		UCB0STE/UCA0CLK (see Notes 1 and 2)	0	Х	1		
		A5 (see Notes 1 and 2)	1	Х	Х		

NOTES: 1. X: Don't care.

- 2. The pin direction is controlled by the USCI module.
- 3. If the I2C functionality is selected, the output drives only the logical 0 to $V_{\mbox{\footnotesize SS}}$ level.

Port P3 pin schematic: P3.1 to P3.5, input/output with Schmitt trigger



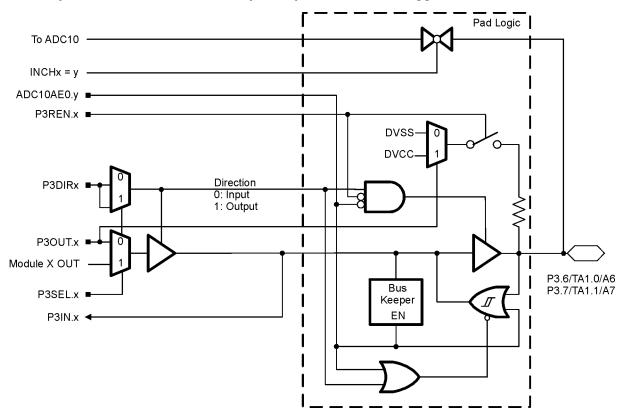
Port P3 (P3.1 to P3.5) pin functions

			CONTROL B	CONTROL BITS / SIGNALS		
PIN NAME (P3.x)	x	FUNCTION	P3DIR.x	P3SEL.x P3SEL2.x = 0		
P3.1/UCB0SIMO/	1	P3.1 (I/O)	l: 0; O: 1	0		
UCB0SDA		UCB0SIMO/UCB0SDA (see Notes 1, 2 and 3)	Х	1		
P3.2/UCB0SOMI/	2	P3.2 (I/O)	l: 0; O: 1	0		
UCB0SCL		UCB0SOMI/UCB0SCL (see Notes 1, 2 and 3)	Х	1		
P3.3/UCB0CLK/	3	P3.3 (I/O)	I: 0; O: 1	0		
UCA0STE		UCB0CLK/UCA0STE (see Notes 1 and 2)	Х	1		
P3.4/UCA0TXD/	4	P3.4 (I/O)	l: 0; O: 1	0		
UCA0SIMO		UCA0TXD/UCA0SIMO (see Notes 1 and 2)	X	1		
P3.5/UCA0RXD/	5	P3.5 (I/O)	l: 0; O: 1	0		
UCA0SOMI		UCA0RXD/UCA0SOMI (see Notes 1 and 2)	Х	1		

NOTES: 1. X: Don't care.

- 2. The pin direction is controlled by the USCI module.
- 3. In case the I2C functionality is selected the output drives only the logical 0 to V_{SS} level.

Port P3 pin schematic: P3.6 to P3.7, input/output with Schmitt trigger



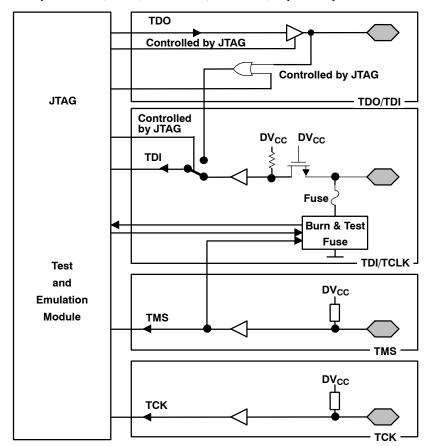
Port P3 (P3.6 and P3.7) pin functions

PIN NAME (P3.x)	х	FUNCTION	ADC10AE0.y	P3DIR.x	P3SEL.x P3SEL2 = 0
P3.6/TA1.0/A6	6	P3.6 (I/O)	0	I: 0; O: 1	0
		Timer1_A2.TA0	0	1	1
		Timer1_A2.CCI0B	0	0	1
		A6	1	X	X
P3.7/TA1.1/A7	7	P3.7 (I/O)	0	I: 0; O: 1	0
		Timer1_A2.TA1	0	1	1
		Timer1_A2.CCl1A	0	0	1
		A7	1	X	X

NOTES: 1. X: Don't care.

APPLICATION INFORMATION

JTAG pins: TMS, TCK, TDI/TCLK, TDO/TDI, input/output with Schmitt trigger



During Programming Activity and During Blowing of the Fuse, Pin TDO/TDI Is Used to Apply the Test Input Data for JTAG Circuitry

APPLICATION INFORMATION

JTAG fuse check mode

MSP430F21x2 devices that have the fuse on the TDI/TCLK terminal have a fuse-check mode that tests the continuity of the fuse the first time the JTAG port is accessed after a power-on reset (POR). When activated, a fuse-check current, I_{TF} , of 1 mA at 3 V or 2.5 mA at 5 V can flow from the TDI/TCLK pin to ground if the fuse is not burned. Care must be taken to avoid accidentally activating the fuse-check mode and increasing overall system power consumption.

Activation of the fuse-check mode occurs with the first negative edge on the TMS pin after power up or if the TMS is being held low during power up. The second positive edge on the TMS pin deactivates the fuse check mode. After deactivation, the fuse check mode remains inactive until another POR occurs. After each POR the fuse check mode has the potential to be activated.

The fuse-check current flows only when the fuse-check mode is active and the TMS pin is in a low state (see Figure 31). Therefore, the additional current flow can be prevented by holding the TMS pin high (default condition).

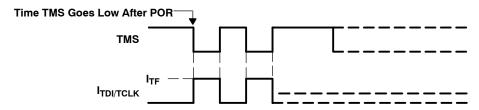


Figure 31. Fuse Check Mode Current

MSP430F21x2 MIXED SIGNAL MICROCONTROLLER

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Data Sheet Revision History

LITERATURE NUMBER	SUMMARY
SLAS578	PRODUCT PREVIEW data sheet release
SLAS578A	PRODUCTION DATA data sheet release
SLAS578B	Corrected timer pin names throughout: TA0_0 changed to TA0.0, TA0_1 changed to TA1.0, TA1_0 changed to TA0.1, TA2_0 changed to TA0.2, TA1_1 changed to TA1.1



PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp (3)
MSP430F2112IPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2112IPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2112IRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2112IRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2112TPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2112TPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2112TRHB	PREVIEW	QFN	RHB	32	250	TBD	Call TI	Call TI
MSP430F2112TRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2112TRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2122IPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2122IPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2122IRHB	PREVIEW	QFN	RHB	32	250	TBD	Call TI	Call TI
MSP430F2122IRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2122IRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2122TPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2122TPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2122TRHB	PREVIEW	QFN	RHB	32	250	TBD	Call TI	Call TI
MSP430F2122TRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2122TRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2132IPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2132IPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2132IRHB	PREVIEW	QFN	RHB	32	250	TBD	Call TI	Call TI
MSP430F2132IRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2132IRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2132TPW	ACTIVE	TSSOP	PW	28	50	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2132TPWR	ACTIVE	TSSOP	PW	28	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM
MSP430F2132TRHB	PREVIEW	QFN	RHB	32	250	TBD	Call TI	Call TI



PACKAGE OPTION ADDENDUM

22-May-2008

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins F	Package Qty	e Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp (3)
MSP430F2132TRHBR	ACTIVE	QFN	RHB	32	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR
MSP430F2132TRHBT	ACTIVE	QFN	RHB	32	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

TBD: The Pb-Free/Green conversion plan has not been defined.

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

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PW (R-PDSO-G**)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

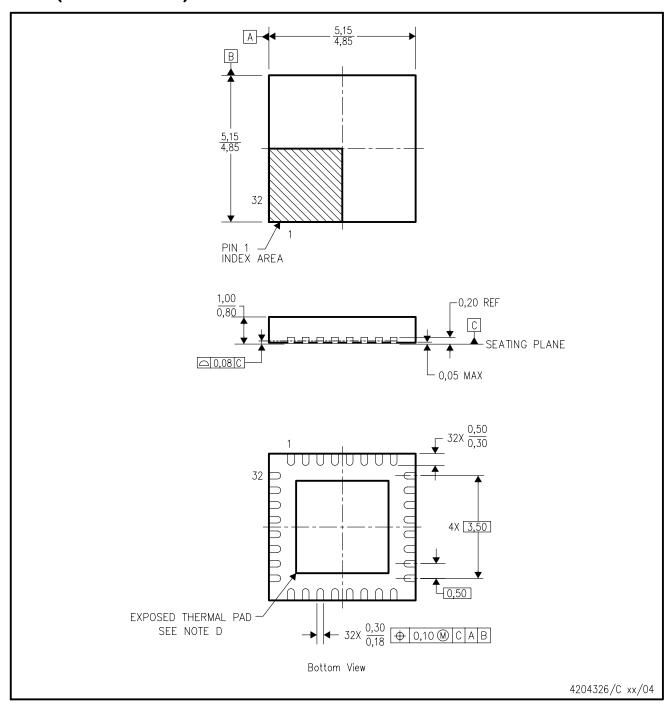
B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

RHB (S-PQFP-N32)

PLASTIC QUAD FLATPACK



NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. QFN (Quad Flatpack No-Lead) Package configuration.
- D The Package thermal pad must be soldered to the board for thermal and mechanical performance. See product data sheet for details regarding the exposed thermal pad dimensions.
- E. Falls within JEDEC MO-220.



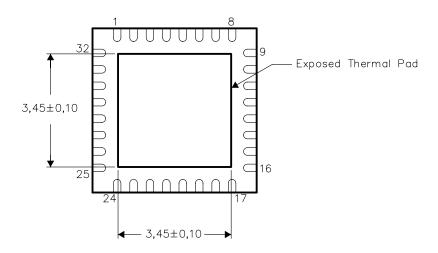


THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, Quad Flatpack No—Lead Logic Packages, Texas Instruments Literature No. SCBA017. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.

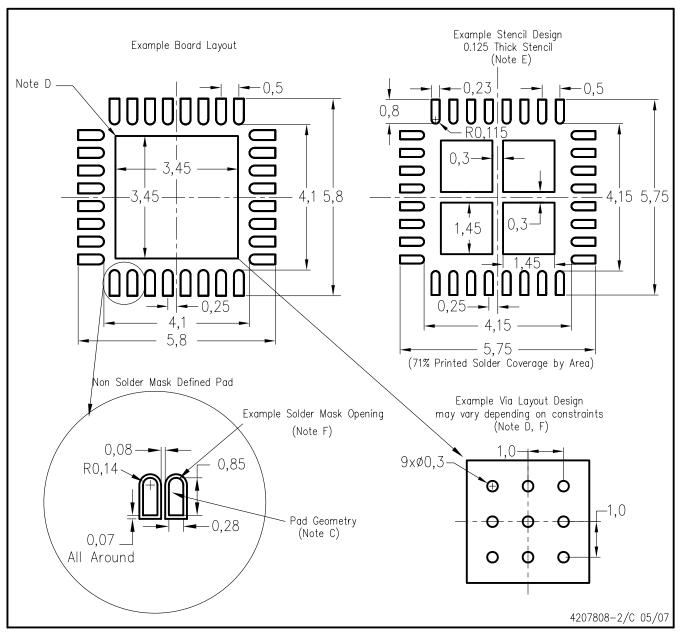


Bottom View

NOTE: All linear dimensions are in millimeters

Exposed Thermal Pad Dimensions

RHB (S-PQFP-N32)



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack Packages, Texas Instruments Literature No. SCBA017, SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com http://www.ti.com>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



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